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BIT ERROR RATE CHARACTERIZATION OF HIGH FREQUENCY
DIGITAL SIGNALS UTILIZING SAMPLING TECHNIQUES

by

William E. Fulmer

A Thesis

Presented to the Graduate Committee

of Lehigh University

in Candidacy for the Degree of

Master of Science

in

Electrical Engineering

Lehigh University

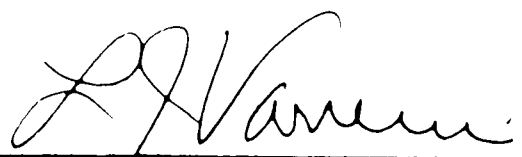
1988

Certificate of Approval

This thesis is accepted and approved in partial fulfillment of the requirements for the degree of Master of Science in the Department of Computer Science and Electrical Engineering.

NOV 17, 1988
(Date)


Professor in Charge


Chairman of Department

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Abstract

This thesis develops a bit error rate (BER) measurement technique based on the gaussian statistics of noise in high frequency baseband digital signals. Commercial BER test equipment is currently available, but is very expensive and requires the use of a known transmitted test pattern.

The laboratory implementation of this technique utilized a Tektronix digitizing oscilloscope to sample the signal and a HP minicomputer to process the data. Experiments were designed to cover a wide range of BER values and plots were made of BER vs. clock phase. It was found that when the noise was "purely" gaussian, there was excellent agreement between measured and predicted BERs at 1 Gb/s bit rates. A matching filter was required in order to achieve these results.

The predicted BER of an optical regenerator was characterized at 1.7 Gb/s at the decision circuit input and showed fair agreement with that measured. Discrepancies as great as an order of magnitude were observed at the BER minimum. This was attributed partially to the error detector limitations and also to the non-gaussian phenomena in the regenerator.

Chapter 1 Introduction

The ever increasing use of higher frequency communication systems has necessitated the development of new bit error rate (BER) measurement techniques to help characterize their performance. The ultra wide bandwidth requirements of these systems complicates the process of making accurate measurements. The test equipment must have a much greater bandwidth than that of the system under test or distortion and measurement error will result.

Commercial BER test equipment is custom manufactured, very expensive, and based on a "brute force" bit by bit comparison of the transmitted and received signals. This limits the usage of the equipment to applications where the transmitted signal is known.

This thesis studies the use of statistical techniques in order to determine the BER. The measuring technique works well on all baseband signals, whether the transmitted pattern is known or not. This allows one to measure the performance of a system while in actual operation rather than under artificial test conditions. The equipment is not nearly as expensive as that of the commercial technique but requires more complicated

computations in determining the BER.

Laboratory implementation of this technique is based upon measurements derived from a digitizing oscilloscope and produced results which are comparable to those of an Anritsu BER test system. The measurements compared BER vs. clock phase and spanned a variety of BER ranges. The sampling technique is more versatile in that it can accommodate a much wider range of input amplitudes than the commercial error detectors. In addition, error detectors often require an amplifier to boost the input signal amplitude which can be a source of distortion and changes in the signal to noise ratio of the waveform being measured.

Chapter 2 of this thesis derives the theory that underlines the procedure being described. The implementation of the technique requires additional considerations which are discussed in Chapter 3. This chapter also includes the methods used to sample and process the data to derive the BER assuming gaussian signal statistics. Since fiber optics is playing an increasing role in modern communications, this thesis also applies the new technique to a 1.7 Gb/s optical regenerator. The procedures and test setup associated with the regenerator are described in Chapter 4. Chapter 5 is devoted to the experimental results obtained and

their comparison with those of an Anritsu error detector. Finally, the conclusions and ideas for future extensions are provided in Chapter 6.

Chapter 2 Bit Error Rate Theory and Derivations

This chapter begins with a brief overview of digital communication systems and bit error rate theory. The operation of an Anritsu error detector is then described. Finally, equations which define the total probability of error are derived. The equations are based on the gaussian nature of random noise sources.

2.1. Digital Communication Systems

The digital signals being analyzed in this thesis will be assumed to contain only binary levels. Therefore, a zero level $V(0)$ or a one level $V(1)$ are the only signal states which can be transmitted or received. Pulse Code Modulation (PCM) is an example of a commonly used transmission code which exhibits these characteristics. The rate at which the digital message is transmitted or received is called the bit rate, B , which has units of bits per second. The two bit rates which are being analyzed within the scope of this thesis are 1.0 and 1.7 Gb/s.

A simplified model for a digital communication data system is shown in Fig. 2.1. The purpose of the system is to transmit the digital message from the source to the

destination. Ideally, the received signal should be an exact replica of the transmitted signal. Unfortunately, the existence of noise in the data channel as well as in

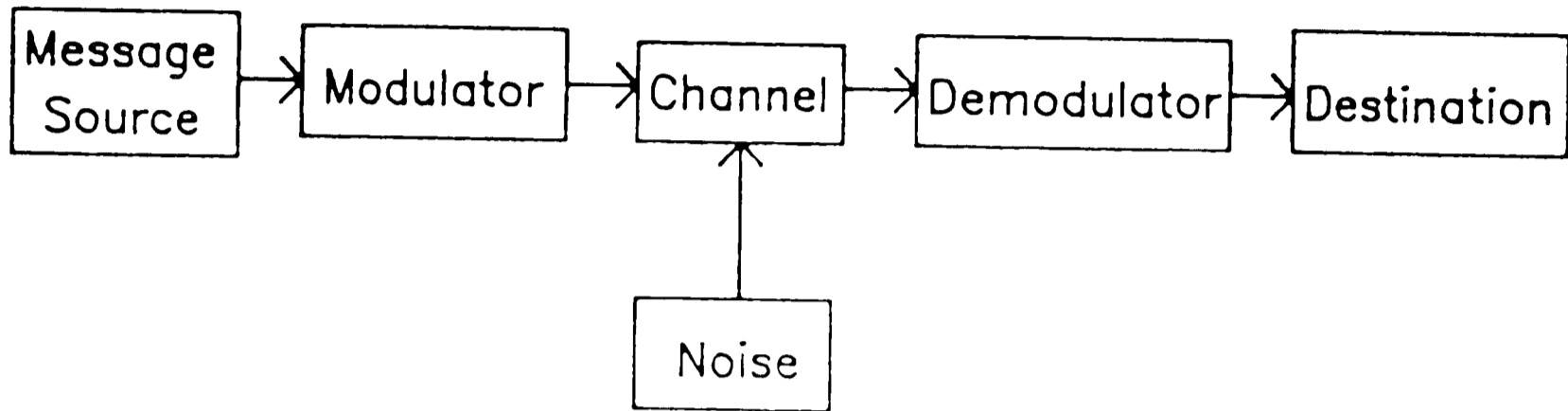


Fig. 2.1. Simplified digital communication system.

the modulator and demodulator circuitry results in the degradation of the original signal when detected at the threshold device.

The received noisy message can be characterized as consisting of two components. The "ideal" digital signal, $V(0)$ and $V(1)$, transmitted at rate B is the first part. The other part is a sample of the additive noise, $n(T_0)$, where T_0 is the sampling point [1]. The communication system can then be modeled from the receiver's point of view, as depicted in Fig. 2.2. The system block diagram shown is that of a typical binary baseband digital receiver [2]. The model is composed of the additive noise process, an equalizing filter, a sampling circuit and a threshold device. $X(t)$ is the

noiseless digital message. $N(t)$ represents the accumulation of all additive noise generated within or injected into the modulator, channel and front end of the

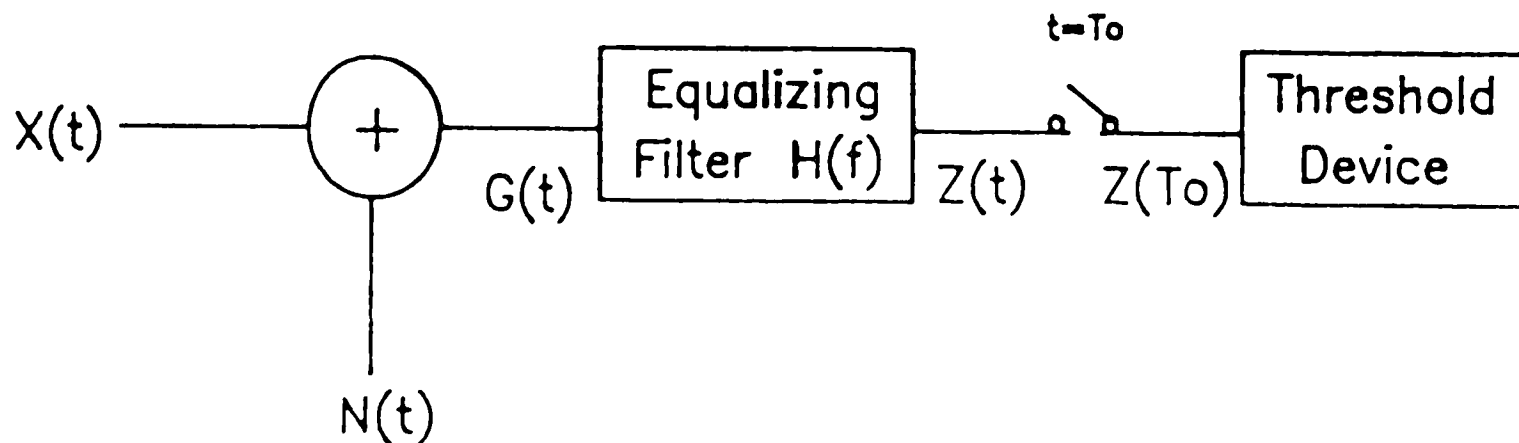


Fig. 2.2. Binary data receiver model.

demodulator. This model serves as a key reference in the derivation of the gaussian equations in Section 2.4.

2.2. Bit Error Rate and Decision Theory

The function of the digital receiver is to determine which digital message was sent and to do so with a minimum of error. This is accomplished through a two step process. First, the received signal is optimized via amplification, pulse shaping and timing circuitry to produce the decision input statistic. This statistic is then injected into the threshold device. A decision circuit is being used as the specific threshold device in this application.

It is the decision circuit which ultimately decides on a binary outcome based on predetermined criteria commonly referred to as the decision rule [2]. The minimax criterion utilized in this thesis selects the decision threshold, D , such that the absolute smallest probability of error is achieved. Once the threshold level is selected, the outcome of the incident decision statistic, $Z(T_0)$, shown in Fig. 2.2, will be determined by

$$\text{Assume } V(1) \text{ transmitted} \leftrightarrow \text{Given } Z(T_0) > D \quad (2.01)$$

and

$$\text{Assume } V(0) \text{ transmitted} \leftrightarrow \text{Given } Z(T_0) < D. \quad (2.02)$$

The probability of error is commonly expressed in terms of the bit error rate (BER). BER is defined as the ratio of the number of bits detected incorrectly to the total number of bits transmitted. In practice, BER is calculated with respect to time over a given interval using

$$\text{BER} = \frac{F_e \text{ (errors/sec)}}{B \text{ (bits/sec)}} = \left(\frac{\text{errors}}{\text{bit}} \right) \quad (2.03)$$

where F_e is the error frequency and B is the bit rate.

An equivalent description of BER is that it represents the probability of a given bit being identified in error. This is obvious upon inspection of the units in Eq. 2.03. BER measurements typically range from 10^{-4} to 10^{-15} depending upon the application.

2.3. Commercial BER Test Equipment

State of the art commercial test equipment is currently available to automatically measure BER at transmission bit rates in excess of 7.0 Gb/s. Anritsu Corp. and Advantest Corp. are among the primary vendors in this field. The equipment is very sophisticated and typically can take six months to a year for delivery. The cost of a generator and receiver pair is quite high, ranging from \$150,000 to \$750,000 depending upon the bit rate required.

An Anritsu model MG642A word generator and model MS65A error detector operate up to 2.0 Gb/s and have been used for all optical regenerator associated measurements. All purely gaussian BER measurements have been made using a 3.0 Gb/s Anritsu model MP1604A generator and model MP1605A detector. The BER measurements performed with this equipment are extremely accurate as well as repeatable. For this reason, the Anritsu error detector

will be used as a benchmark for comparison of the proposed measurement technique which will be described shortly.

A block diagram which portrays the functionality of the 2.0 Gb/s MS65A error detector [3] is shown in Fig. 2.3. The data pattern input which is to be measured is injected into a pulse shaper where a variable threshold decision is made. A 1:4 demultiplexer is then utilized to divide the 2 Gb/s series data stream into four slower 500 Mb/s parallel signals. This is an elaborate but necessary complication since the Exclusive-OR gates performing the comparator function will not operate much above 500 Mb/s.

A reference pattern generator is incorporated within the detector itself. This generator outputs the identical pattern which was originally transmitted by the MG642A generator through a digital channel to the detector. The replicated pattern is also demultiplexed to four parallel data streams which are input into the Exclusive-OR gates along with the four parallel lines being tested. A "brute force" comparison is then made between transmitted and received data and errors are detected bit by bit. This method is extremely accurate since the error detector knows the exact transmitted pattern in advance.

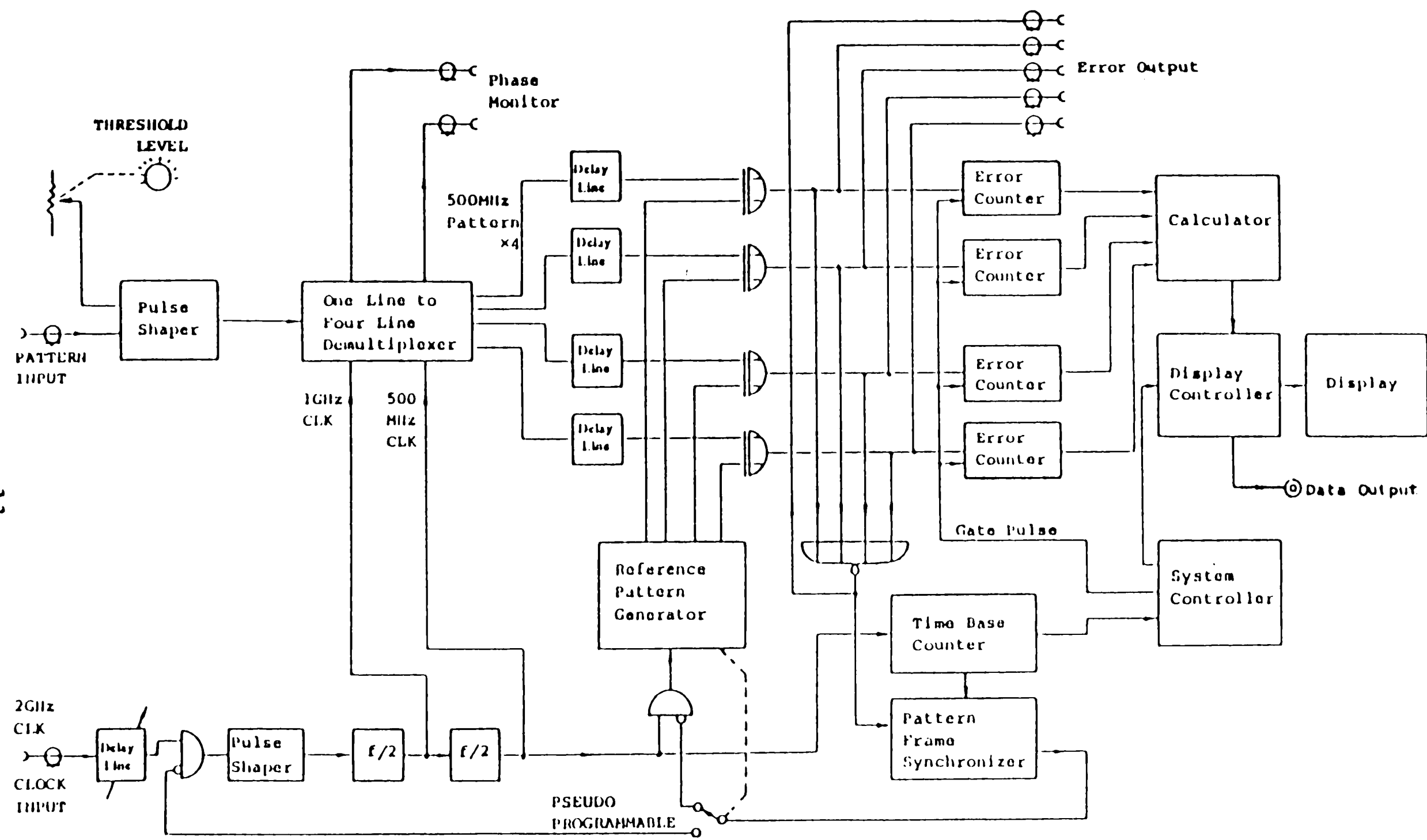


Fig. 2.3. Anritsu MS65A error detector block diagram.

In order for this detection scheme to function, the four parallel lines being measured must be phase matched to compensate for propagation delays and to achieve optimal timing performance. A pattern frame synchronization circuit must also be employed to align the two groups of parallel bit streams with each other. The patterns must be matched up to coincide at the inputs of the Exclusive-OR gates in order to obtain a valid error count. Synchronization is obtained by inhibiting the clocking of the reference pattern generator until the instantaneous error counter stops overflowing prior to the clock counter.

Each Exclusive-OR gate is monitored by a dedicated error counter. The counter is incremented each time the Exclusive-OR gate inputs are different, implying that an error has occurred. The errors are then totalized during a known time interval and converted into bit error rate using the measured clock rate and Eq. 2.03. The BER is then displayed on the LED front panel.

2.4. Derivation of Gaussian BER Equations

An extensive discussion of the sampler output, $Z(T_0)$, will now be presented in order to characterize the signal for a hypothetical analysis of the probability of

error. In this section, the noise sources and their associated probability distribution functions are described. The equations are then derived which define the total probability of error. Finally, an approximation will be introduced which greatly simplifies the numerical calculations.

Random noise is a phenomena which occurs within virtually all electronic circuitry and transmission channels [4]. Thermal noise, shot noise, 1/f noise and amplifier noise are common stationary random processes which are well described by gaussian statistics. It is then possible to assume that the noise source $N(t)$ in Fig. 2.2 can be represented with a gaussian probability function. Without loss of generality, a function will be assumed with zero mean value and a mean-square value as described by

$$\overline{N(t)} = \lim_{\tau \rightarrow \infty} \frac{1}{\tau} \int_{-\tau/2}^{\tau/2} N(t) dt = 0 \quad (2.04)$$

and

$$\overline{N^2(t)} = \lim_{\tau \rightarrow \infty} \frac{1}{\tau} \int_{-\tau/2}^{\tau/2} |N(t)|^2 dt = \sigma^2 \quad (2.05)$$

where σ represents the rms noise voltage or current and τ is the time interval.

The result of adding a zero mean gaussian random variable to an idealized signal $X(t)$ with binary levels V_{X0} , V_{X1} is another gaussian random variable with means V_{X0} , V_{X1} and variances σ_{X0}^2 , σ_{X1}^2 , respectively [1]. This is proven by a theorem stating that linear transformations on gaussian random variables yields gaussian random variables [5]. Combining this theorem with the principle of linear superposition yields

$$G(t) = N(t) + X(t) \quad (2.06)$$

where $G(t)$ has the gaussian distribution just described. The equalizing filter is a linear, time-invariant circuit whose output $Z(t)$ is given by the time convolution

$$Z(t) = \int_{-\infty}^{\infty} h(\tau) g(t-\tau) d\tau. \quad (2.07)$$

$Z(t)$ is also gaussian by reason of the linear transformation theorem. $Z(t_0)$ represents the value of $Z(t)$ at sampling time t_0 .

The probability density functions for $Z(T_0)$, the threshold circuit input, can now be written by using the constraints assumed. If a binary zero level is transmitted, the gaussian probability density function can be expressed as [6]

$$P_0(y) = \frac{1}{\sqrt{2\pi}\sigma_0} e^{-(y-V_0)^2/2\sigma_0^2}. \quad (2.08)$$

Similarly, in the case of a one level, the probability density function is

$$P_1(y) = \frac{1}{\sqrt{2\pi}\sigma_1} e^{-(y-V_1)^2/2\sigma_1^2}. \quad (2.09)$$

Both functions are shown in Fig. 2.4 where y represents the signal amplitude and $P(y)$ is the normalized probability of occurrence of the amplitude. V_0 and V_1 represent the mean transformed binary levels of $Z(T_0)$ with variances σ_0^2 and σ_1^2 , respectively. In general, σ_1 will be larger than σ_0 due to the fact that the noise at each level contains contributions proportional to the signal itself [7].

In reference to the decision level, D , shown in Fig. 2.4, there are two possible types of errors which could occur. The hatched areas in Fig. 2.4 provide a graphical representation of the probability of each of the errors. The probability of a "false alarm", $P(E_1/0)$, is given by the integral of the tail of $P_0(y)$ as expressed by

$$P(E_1/0) = \int_D^{\infty} \frac{1}{\sqrt{2\pi}\sigma_0} e^{-(y-V_0)^2/2\sigma_0^2} dy. \quad (2.10)$$

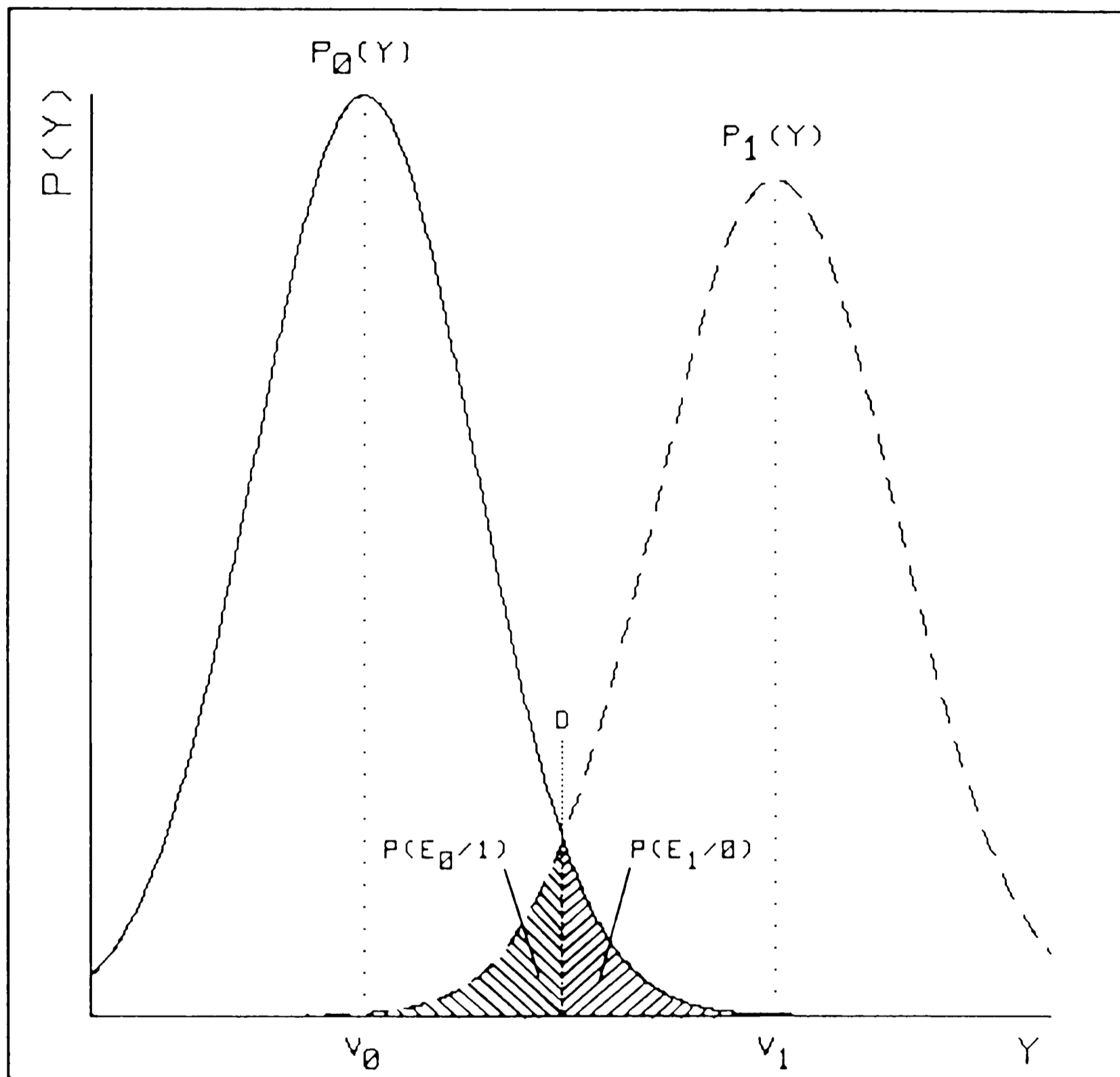


Fig. 2.4. Binary detected probability density functions.

Similarly, the probability of the receiver choosing zero when a one was transmitted, $P(E_0/1)$, is given by

$$P(E_0/1) = \int_{-\infty}^D \frac{1}{\sqrt{2\pi}\sigma_1} e^{-(Y-V_1)^2/2\sigma_1^2} dy. \quad (2.11)$$

The total probability of error can then be written as

$$P(E) = P_0P(E_1/0) + P_1P(E_0/1) \quad (2.12)$$

where $P(E_1/0)$ and $P(E_0/1)$ are the conditional probabilities that a bit is misidentified and P_0 , P_1 are the probabilities that a zero, one is transmitted, respectively.

$P(E_1/0)$ can be simplified by expressing Eq. 2.10 in terms of the complementary error function, $\text{Erfc}(x)$. To accomplish this, the equation is normalized for zero mean and unity variance using the substitution variables

$$z = \frac{Y-V_0}{\sigma_0} \quad (2.13)$$

and

$$dz = \frac{1}{\sigma_0} dy \quad (2.14)$$

Substitution of Eq. 2.13 and Eq. 2.14 into Eq. 2.10

yields

$$P(E_1/0) = \int_{\frac{D-V_0}{\sigma_0}}^{\infty} \frac{1}{\sqrt{2\pi}} e^{-z^2/2} dz. \quad (2.15)$$

This can be further simplified by defining

$$Q_0 = \frac{|D - V_0|}{\sigma_0} \quad (2.16)$$

and expressing Eq. 2.15 as

$$P(E_1/0) = \int_{Q_0}^{\infty} \frac{1}{\sqrt{2\pi}} e^{-z^2/2} dz. \quad (2.17)$$

The general Erfc(x) definition is given by [6]

$$\text{Erfc}(x) = \int_x^{\infty} \frac{1}{\sqrt{2\pi}} e^{-z^2/2} dz. \quad (2.18)$$

Using Eq. 2.18, Eq. 2.17 can be rewritten as

$$P(E_1/0) = \text{Erfc}(Q_0) = \int_{Q_0}^{\infty} \frac{1}{\sqrt{2\pi}} e^{-z^2/2} dz. \quad (2.19)$$

Since the integral in Eq. 2.19 cannot be evaluated in closed form, the approximation shown in Eq. 2.20 will be made in order to simplify numerical calculations [6].

$$\text{Erfc}(X) \simeq \frac{1}{X\sqrt{2\pi}} \left(1 - \frac{1}{X^2}\right) e^{-X^2/2}, \quad x \gg 1 \quad (2.20)$$

Calculations which compare Eq. 2.20 and Erfc(X) tables indicate an error of 1.1% at $Q = 4$ and 0.15% at $Q = 6$. This degree of error is tolerable and therefore the approximation is justified. Finally, substitution of Eq. 2.20 into Eq. 2.19 yields

$$P(E_1/0) \simeq \frac{1}{Q_0\sqrt{2\pi}} \left(1 - \frac{1}{Q_0^2}\right) e^{-Q_0^2/2}. \quad (2.21)$$

Fig. 2.5 shows the conditional probability of error vs. Q relationship for error rates between 10^{-3} and 10^{-12} . It is apparent from the plot that the probability of error varies drastically as a function of Q , especially at low BER. This implies that Q will need to be determined quite accurately and repeatably in order to provide consistent BER measurements. An analogous simplification of $P(E_0/1)$ yields

$$P(E_0/1) \simeq \frac{1}{Q_1\sqrt{2\pi}} \left(1 - \frac{1}{Q_1^2}\right) e^{-Q_1^2/2} \quad (2.22)$$

where

$$Q_1 = \frac{|D - V_1|}{\sigma_1}. \quad (2.23)$$

The overall probability of error $P(E)$ can now be expressed in simplified form. Substitution of Eq. 2.21 and Eq. 2.22 into Eq. 2.12 yields

$$P(E) = \frac{1}{\sqrt{2\pi}} \left\{ \frac{P_0}{Q_0} \left(1 - \frac{1}{Q_0^2} \right) e^{-Q_0^2/2} + \frac{P_1}{Q_1} \left(1 - \frac{1}{Q_1^2} \right) e^{-Q_1^2/2} \right\}. \quad (2.24)$$

In Eq. 2.24, Q_0 and Q_1 have been well defined, however, probability assignments have yet to be made with respect to P_0 and P_1 . The most straight forward treatment of these variables would be to use the "a priori" probabilities, where information is known in

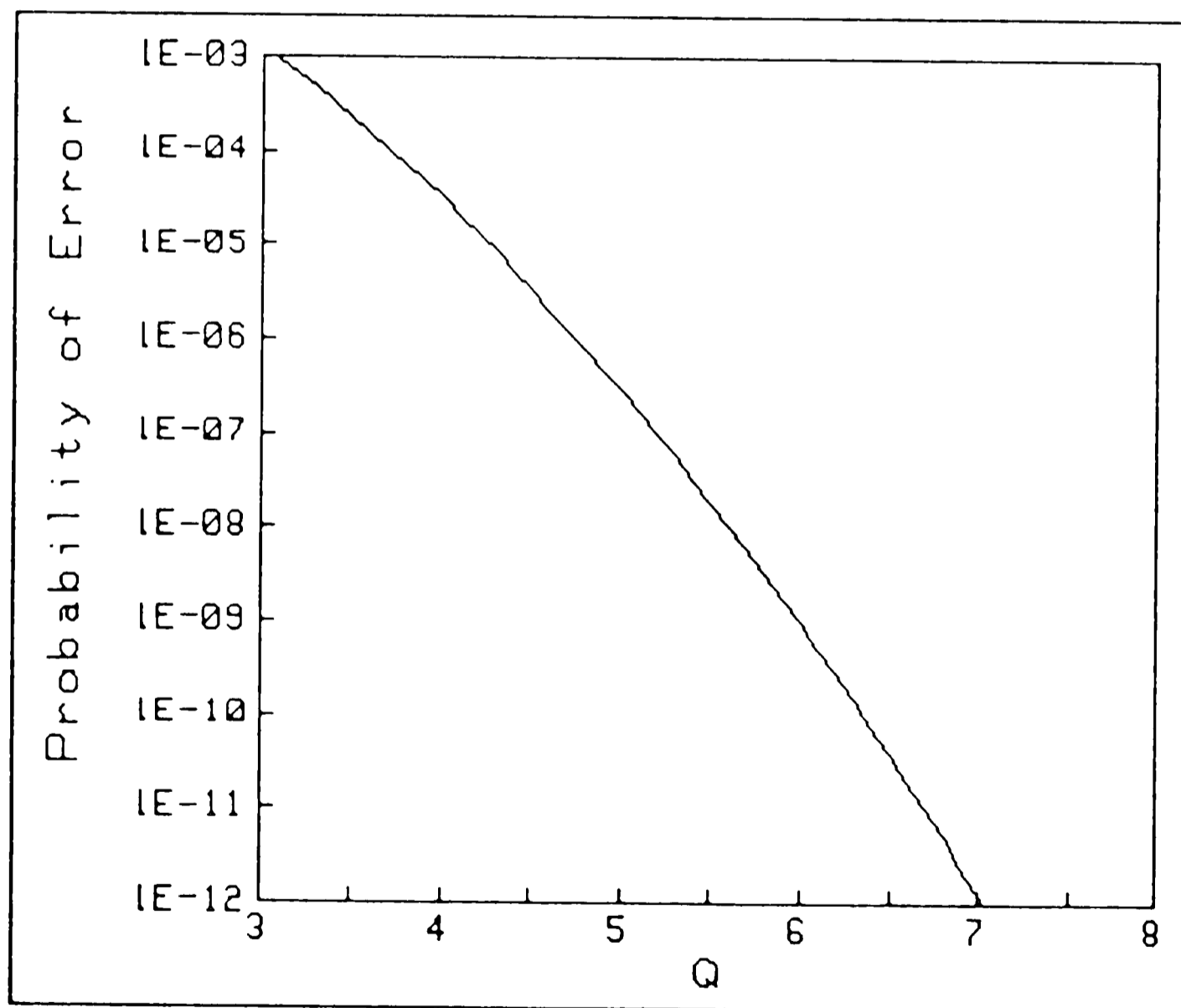


Fig. 2.5. Conditional probability of error vs. Q .

advance about the duty cycle of the transmitted data [1]. A 50% pseudo-random data pattern is used for all measurements in this thesis as well as in many communication systems which dictates that

$$P_0 = P_1 = \frac{1}{2} . \quad (2.25)$$

A more general approach, however, will be used instead in order to generalize the equation for unknown duty cycles. A conditional probability, known as "a posteriori" probability, will be calculated based on the observation at the receiver. The decision criterion used here, "maximum a posteriori criterion", chooses the hypothesis that has the maximum probability associated with it.

Therefore, for a given threshold D , if a zero is detected it should be assumed that a zero was transmitted. This is a valid assumption since the probability of a zero sent given a zero detected is typically much greater than the probability of a one sent given a zero detected for the range of error rates being evaluated. Likewise, if a one is detected, it should be assumed that a one was transmitted. This decision process will be repeated with a total sample size of N_s values at each clock phase sampled. This allows one to

determine P_0 and P_1 experimentally as

$$P_0 = \frac{N_0}{N_s} \quad (2.26)$$

and

$$P_1 = \frac{N_1}{N_s} \quad (2.27)$$

where N_0 and N_1 are the number of zeros and ones, respectively. The sampling process itself will be described in the next chapter.

Chapter 3 Implementation of Gaussian BER Measurements

This chapter discusses the implementation of the theory presented in Chapter 2 and explains the measurement techniques used. A purely gaussian decision statistic is produced and characterized in order to verify the measurement techniques in an optimal environment. This eliminates the introduction of non-gaussian phenomena as well as timing and interference problems which can often occur in optical regenerators. In Chapter 4, a more specific and practical application will be pursued in the evaluation of a 1.7 Gb/s optical regenerator at the decision circuit input.

3.1. Digital/Gaussian Noise Source

The "ideal" noisy digital/gaussian signal is synthesized using the arrangement of Fig. 3.1. The circuit combines a digital word of variable amplitude with a band-limited noise source using a resistive power combiner/divider. The composite noisy output signal can be assumed to be representative of that which exists in communication systems circuitry. The system noise originates predominantly in gaussian noise sources as

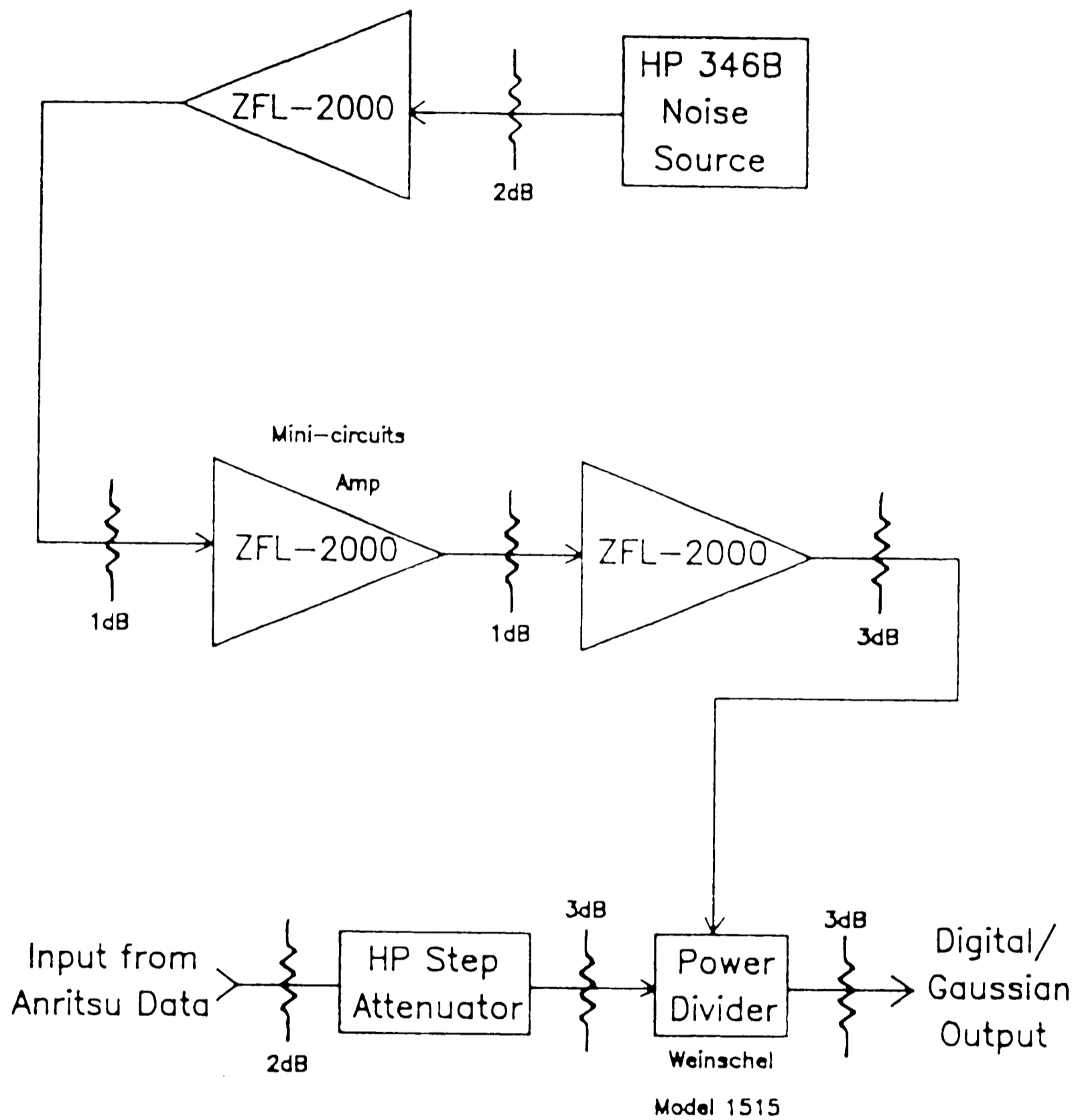


Fig. 3.1. Digital/gaussian noise combiner circuit.

described in Section 2.4. A picture of a typical digital/gaussian output waveform is shown in Fig. 3.2. This particular 1.7 Gb/s waveform exhibits a minimum BER of 1.0×10^{-6} using the error detector.

The noise source selected is an HP model 346B noise diode. It is characterized by a low VSWR and broadband

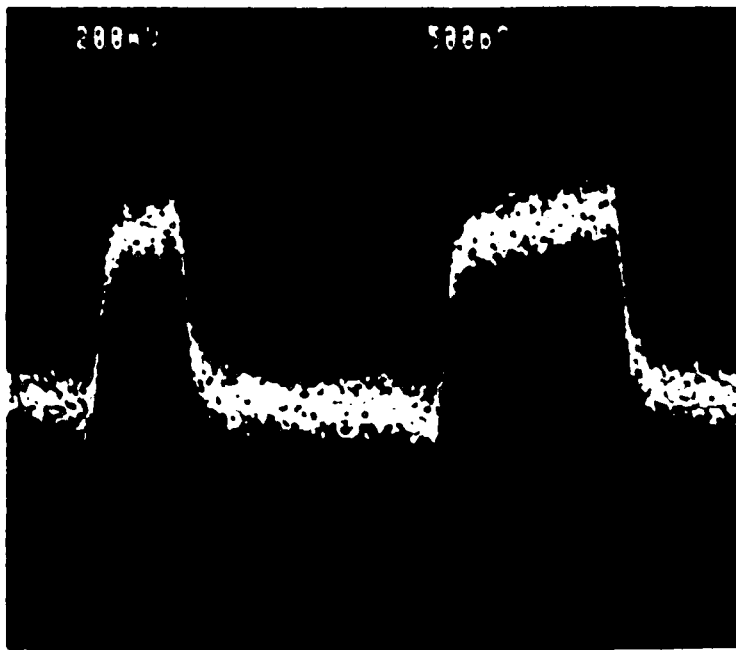


Fig. 3.2. Digital/gaussian output waveform which exhibits a minimum BER of 1.0×10^{-6} .

output performance from 10 Mhz to 18 Ghz. This source drives a series of cascaded broadband amplifiers. These are used to amplify the noise to a voltage amplitude which is sufficient to induce errors in the range of BER= 10^{-9} . The three amplifiers also perform a buffering function between the noise source and the resistive combiner. Interstage attenuators are incorporated in the RF path to reduce microwave reflections and to optimize

the impedance match. The bandwidth of the cascaded amplifiers is 10 Mhz to 2 Ghz. Therefore, the resultant noise signal to the combiner is classified as band-limited white noise (10 Mhz - 2 Ghz).

The Anritsu digital word generator is used as the signal source. A 50% pseudo-random NRZ data stream of $2^{15}-1$ bits is selected to be the test pattern since it contains many binary sequences typical of PCM signals. The generator data output passes through a programmable RF attenuator which can be varied in 1 dB steps. This allows one to change the Signal to Noise, S/N, ratio as required to achieve the desired BER performance during testing. The data transmission rate is intended to be fixed at 1.7 Gb/s, however, the BER is also evaluated at 1.0 Gb/s for reasons to be discussed later.

3.2. Test Setup for Gaussian Measurements

The digital/gaussian noise source developed in Section 3.1 has been incorporated into a computer controlled measurement system. A block diagram of the test setup is shown in Fig. 3.3. The system computer is an HP 300 Series computer which controls all key test equipment via the GPIB interface. This includes the sweep oscillator, the digitizing oscilloscope, as well as

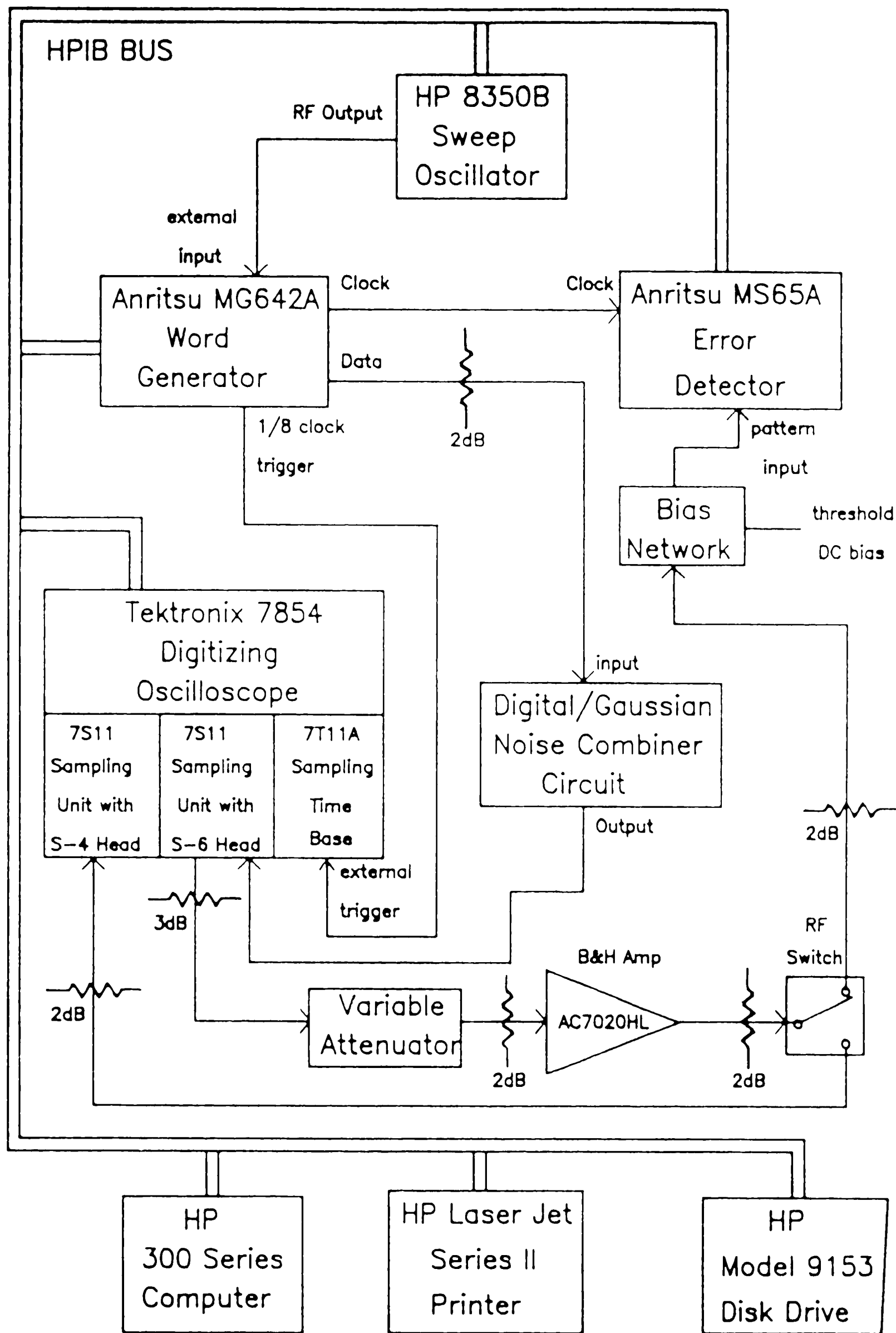


Fig. 3.3. Gaussian measurement test system.

the Anritsu BER equipment. In addition, an HP Laser Jet Series II Printer is interfaced to the system using an HP-IB to parallel I/O converter to provide hi-speed test data output.

As indicated in Section 3.1, the digital signal originates in the Anritsu word generator. An HP model 8350B Sweep Oscillator is used to control the digital transmission rate through the external clocking input of the generator. The generator is equipped with an internal clock; however, it does not provide a signal which is stable enough to assure optimal timing results. An external clock signal also adds the capability to program the bit rate using software commands. The word generator utilizes the clock input as a timing reference in deriving the clock, data and trigger output waveforms. In this way, a fixed phase relationship is maintained between the signal outputs which is critical in making stable measurements.

Gaussian noise is mixed with the generator data signal in the combiner circuit. The noisy combiner output then passes through a Tektronix S-6 feed-thru sampling head in the right vertical channel of the oscilloscope. This allows the intermediate signal to be previewed with minimal perturbations when the system output is terminated into the error detector. The

typical signal amplitudes at the output of the S-6 head are in the range of 200 to 500 mVpp.

A post amplifier circuit boosts this amplitude in order to satisfy the 0.7 to 2.0 Vpp data input specification of the detector. A B&H Electronics model AC7020HL amplifier is selected for the application and is designed into the output path such that it causes minimal degradation in the signal being measured. The amplifier features an ultra wide bandwidth of 7.5 Ghz and a VSWR of 1.5 which helps to preserve the square pulse shape. In-line attenuators are used to reduce interstage reflections.

The excellent amplifier quality and RF matching is a good design practice to follow when making measurements with the error detector. However, it is important to note that the sampling technique requires no amplifier at all since it could sample the S-6 output directly. The exact same signal must be analyzed by both techniques in order to obtain a valid comparison of the two. In this case it is made after the post amp and any degradation will be common to both. An additional variable attenuator has been provided to equalize all outputs to approximately 800 to 900 mVpp. This is necessary to eliminate erroneous results which could be caused by sampling distortion which can occur in the S-4 sampling head at

input levels above 1.0 Vpp.

The post amplified signal is input into an RF switch. The switch is used to direct the output either to the detector or to the AC-coupled S-4 sampling head located in the left vertical channel of the oscilloscope. It is the S-4 head which is ultimately sampling the decision statistic and providing the test data used to calculate the BER. The effects of oscilloscope sampling noise and quantizing error are assumed to be negligible in this application. A bias network has been provided at the detector input to allow its threshold level to be varied with greatly increased resolution using an external voltage supply. This is required to achieve the absolute optimal BER during detector measurements.

3.3. Discussion of Digitizing Technique

The S-4 sampling head in the oscilloscope constructs a digital representation of the data stream being measured [8]. A sequential equivalent-time sampling process is employed in order to create the most accurate facsimile for this type of repetitive input signal. This method allows an equivalent bandwidth to be achieved which is much larger than in real time sampling systems. In sequential equivalent time sampling, many cycles of an

input signal are translated into a single cycle of low frequency digitized points. Hi-speed digital pulse edges that would otherwise defy measurement can be accurately digitized using this technique. A graphical representation of this process is shown in Fig. 3.4.

The S-4 sampling head was specifically selected to sample the data signal for a variety of reasons. The S-4

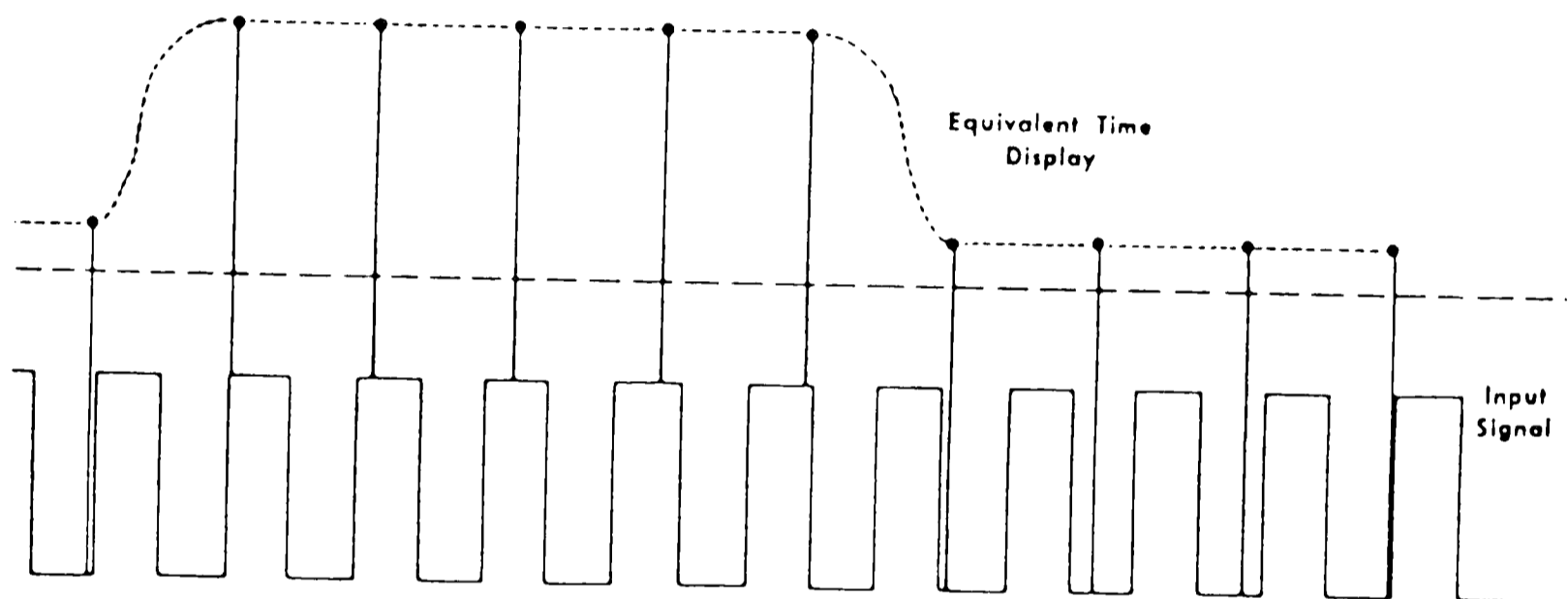


Fig. 3.4. Equivalent time display of real time signal.

features 14 Ghz equivalent bandwidth and a quality 50 ohm internal termination. It also provides a superior dot response optimization than the S-6 head. Non-optimized dot response is a source of waveform distortion and must be avoided.

The displayed waveform in Fig. 3.2 is typical of

that created using a pattern sync trigger from the generator into the Tektronix model 7T11A sampling time base. A 1/8 clock trigger will now be used instead which will trigger the oscilloscope every eight clock pulses. This causes the bits of the pseudo-random pattern to be continuously superimposed on top of each other to form an eye diagram of the data stream. An eye diagram of the same data signal shown in Fig. 3.2 is portrayed in Fig. 3.5.

The eye diagram provides a qualitative description of the digital integrity of the data signal. In general,

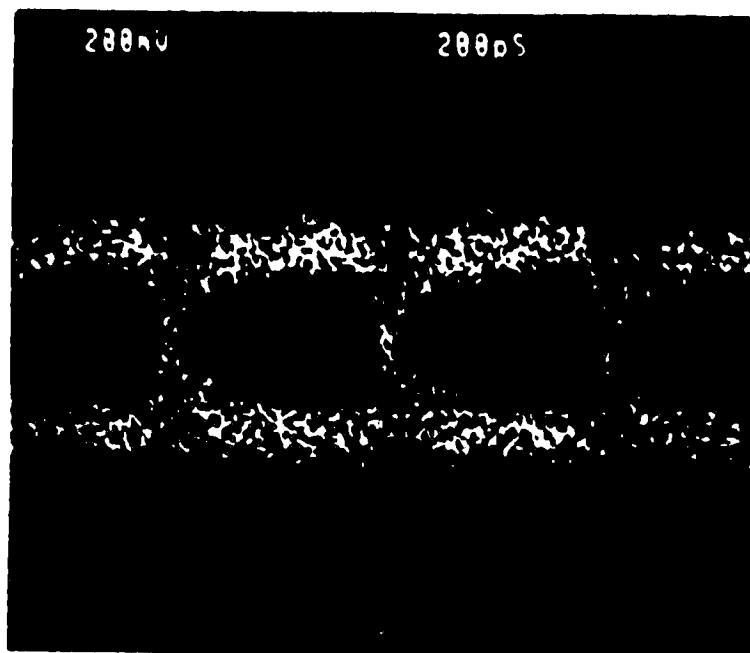


Fig. 3.5. Digital/gaussian eye diagram which exhibits a minimum BER of 1.0×10^{-6} .

the more "open" the aperture of the eye, the better the quality of the BER performance. The optimal eye pattern is obtained by compromising system bandwidth to achieve a

trade-off between system noise and intersymbol interference [9]. These are the two phenomena which limit the overall BER quality. Bandwidth should be minimized to reduce eye closure due to system noise. On the other hand, bandwidth should be maximized in order to reduce the effects of intersymbol interference.

3.4. Statistical Determination of BER

The eye diagrams are used to calculate the BER for a given threshold D and clock phase. Calculation of each BER involves a two step process. First, a valid sample set of data points must be accumulated. Then, the test data must be interpreted and quantized to derive values for all variables in Eq. 2.24. Software algorithms have been written to perform each of these tasks and a listing is available in Appendix A. Computer generated plots are made of BER vs. clock phase at the optimal threshold level. Plots of BER vs. data threshold can also be generated for a given clock phase.

A total of 36 sampling phase subsets are defined between adjacent crossovers on the eye diagram. The first phase subset starts at the left crossover at 0° clock phase and the last ends at the right crossover at 360° . The oscilloscope digitizes the eye diagram into

512 equi-distant points. The point numbers of the 0 and 360° phase subsets are then determined using the digital cursors. Finally, the location by point number of the center of each subset is calculated in 10° increments.

A sample size of 900 samples for each phase subset is chosen based on computer RAM memory limitations. A sampling aperture 5 points wide about each center is used in accumulating the data samples. This dictates that the center point for a given phase as well as the two points to the right and left are all considered valid points for that phase. The oscilloscope continuously repeats the sampling process until all 36 subsets have acquired 900 voltage samples. The waveform can be sampled as long or as often as required since it is characterized by stationary time-invariant processes as discussed previously. All sampling data is stored on 3.5 inch microfloppy disks to allow subsequent processing.

The Tektronix digitizing process creates one serious problem for obtaining valid BER samples by adding phantom points to the digital display. It does this in order to fill in missing points so that the display is always exactly 512 points and each point number corresponds to the same position. Phantom points are inserted by the oscilloscope precisely between adjacent valid points and can represent up to 1% of the population. These points

can cause large errors and must be removed from the sample since points placed between V_0 and V_1 will appear in the middle of the eye diagram. The algorithm therefore invalidates any data point number X during the sampling process whose value satisfies

$$\left| \frac{V(X-1) + V(X-1)}{2} - V(X) \right| \leq .002(V_{\max} - V_{\min}) \quad (3.01)$$

In Eq. 3.01, $V(X)$ is the voltage at point number X and V_{\max} , V_{\min} are the absolute maximum, minimum voltages of the first digitizing pass, respectively.

Once all 36 subsets are filled with valid samples, BER calculations can begin. Since the best possible BER performance is desired, the phase which exhibits minimum BER and its associated threshold level must first be identified. This is accomplished by determining P_0 , P_1 , V_0 , V_1 , σ_0 and σ_1 for each subset and then calculating BER using Eq. 2.24 with all threshold levels between V_0 and V_1 in 0.1% increments. All combinations of phase and threshold level are checked to find the optimal phase and threshold. This overall optimal threshold is then used to recalculate BER in Eq. 2.24 with the specific P_0 , P_1 , V_0 , V_1 , σ_0 and σ_1 from each of the 36 subsets. The resulting data is then plotted as optimal BER vs. clock phase. Test results depicting these types of plots are

shown in Chapter 5.

The software which determines P_0 , P_1 , V_0 , V_1 , σ_0 and σ_1 for a given phase subset is now briefly described. It first establishes the minimum and maximum values of the voltages and then creates a histogram of voltage cell vs. number of occurrences for each cell. This is done by dividing the voltage span into 100 equal cells and then binning all data samples into the appropriate cell. A typical histogram is shown in Fig. 3.6 for a waveform which exhibits a minimum BER of 1.6×10^{-8} at 180° phase.

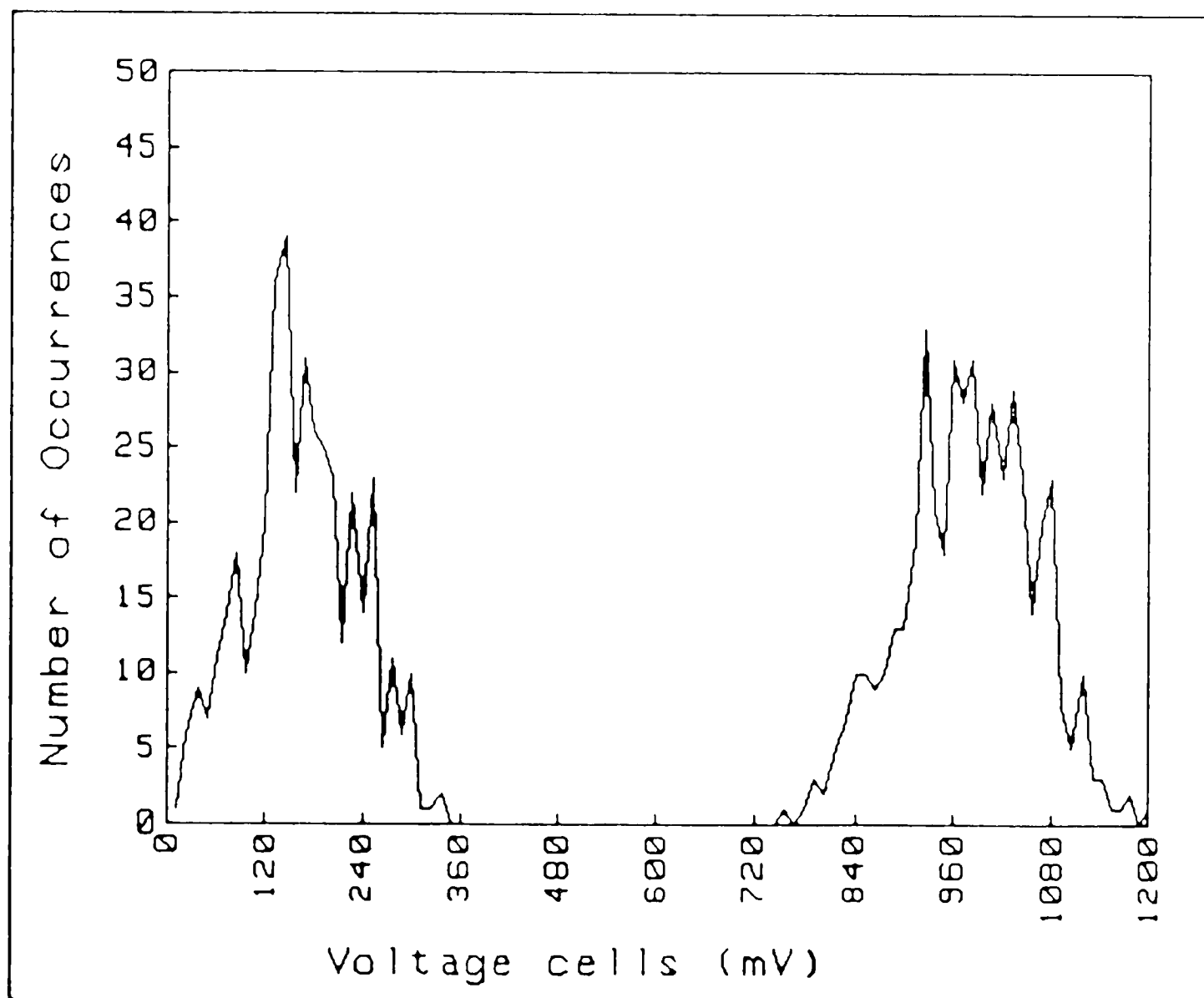


Fig. 3.6. Histogram of voltage cell vs. number of occurrences for a waveform which exhibits a minimum BER of 1.6×10^{-8} at 180° .

Originally, the cells of maximal occurrence in the histogram were intended to be used to determine V_0 and V_1 . This is justified since the average V_0 and V_1 should be the most often occurring voltage cells. After observing poor BER repeatability in initial experimental results, the sample means have been used instead. The histogram is still useful as a graphical representation of the voltage distribution for each subset, however, it will not actually be used in calculating the BER.

Calculation of V_0 and V_1 is achieved by first dividing the subset samples into two groups, V_0 and V_1 . The subset sample mean \bar{V} as expressed by

$$\bar{V} = \sum_{k=1}^{N_s} \frac{S_k}{N_s} \quad (3.02)$$

where S_k is sample point k . It is used as the decision criteria in Eq. 2.01 and Eq. 2.02 to associate each sample value with the appropriate zero (group V_0) or one (group V_1) gaussian distribution. P_0 and P_1 are calculated using Eq. 2.26 and Eq. 2.27 since the total number of zeros N_0 in group V_0 and ones N_1 in group V_1 can be totalized. Each group is then evaluated separately using

$$V_0 = \sum_{k=1}^{N_0} \frac{V_{0k}}{N_0} \quad (3.03)$$

and

$$v_1 = \sum_{k=1}^{N_1} \frac{v_{1k}}{N_1} \cdot \quad (3.04)$$

The sample variance S^2 is defined by Groeneveld [10] as

$$s^2 = \sum_{i=1}^n \frac{(X_i - \bar{X})^2}{(n - 1)} \quad (3.05)$$

and is used to calculate σ^2 . The factor $n-1$ in the denominator compensates for finite sample size to assure that S^2 is an unbiased estimator of σ^2 . σ_0 and σ_1 can then be expressed as

$$\sigma_0 = \sqrt{\sum_{k=1}^{N_0} \frac{(V_{0k} - V_0)^2}{(N_0 - 1)}} \quad (3.06)$$

and

$$\sigma_1 = \sqrt{\sum_{k=1}^{N_1} \frac{(v_{1k} - v_1)^2}{(N_1 - 1)}} \cdot \quad (3.07)$$

Computer programs to implement these equations are included in Appendix A.

Chapter 4 Optical Regenerator Measurements

In this chapter, the functionality of a typical optical regenerator is explained. The actual test setup used in making the regenerator BER measurements is also described. The overall function of the regenerator is to receive a degraded optical input and then to transmit an error free optical output. The S/N ratio and pulse shape of the regenerator output must be as good as the original data of the source transmitter to achieve optimal system performance.

4.1. Regenerator Theory

In a digital communication system, a laser source launches optical data pulses into a single-mode 1.3 micron optical fiber. The pulses degrade as they propagate down the fiber due to channel noise, attenuation, as well as dispersive effects. After passing through kilometers of fiber, the pulses will become severely distorted and exhibit poor S/N ratios. An optical regenerator is then used in the communication system to regenerate the source signal when the performance drops below an acceptable sensitivity level. The sensitivity of an optical receiver is generally

expressed in terms of the minimum received optical power necessary to achieve a specific BER.

A simplified block diagram for a 1.7 Gb/s optical regenerator is shown in Fig. 4.1. The optical signal is detected at the input of the regenerator by an avalanche photo-detector diode. The photo-detector converts the light pulses into current pulses which are then converted into voltage at the receiver output. The transimpedance of the low noise pre-amplifier must be optimized for the best gain versus bandwidth trade-off. The input sensitivity is dominated by the S/N ratio established within the optical receiver. This assumes that the linear channel noise and the effects of intersymbol interference are minimal.

The output of the receiver passes through a linear channel which performs pulse shaping as well as automatic gain control functions. The signal is then split into two parts using a power divider buffer circuit. One of the outputs is injected directly into the data input of the decision circuit. The other output is used to provide clock recovery and retiming tasks. The recovered clock signal is directed into the clock input of the decision circuit and the clock phase is set for optimal performance. The output of the decision circuit is noise free, ideally. This waveform, which has greatly

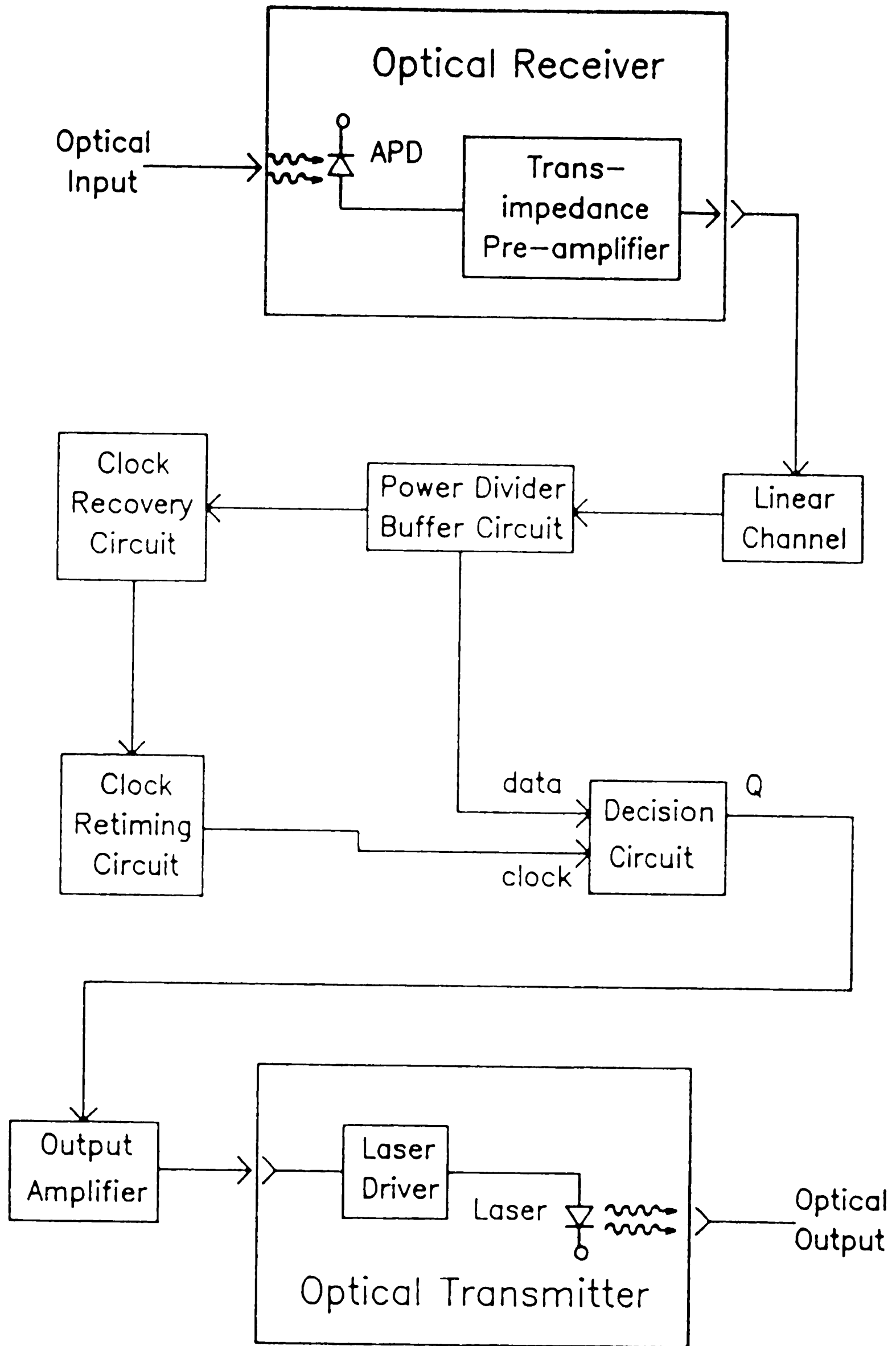


Fig. 4.1. Optical regenerator block diagram.

improved S/N ratio, feeds into the laser driver. The laser driver then modulates the laser to launch the digital signal onto the output fiber. This fiber terminates at the destination receiver or another optical regenerator.

4.2. Regenerator Test Setup

The BER of the optical regenerator is evaluated at the input to the decision circuit. This characterizes the best possible performance achievable by the decision circuit. Modifications to the regenerator have been made in order to accomplish this. The new configuration is shown in Fig. 4.2. The fiber optics are now connected input to output via optical hardware to simulate an optical link. Also note that the decision circuit has been removed from the system.

The optical output passes through a variable optical attenuator. The optical attenuation is varied to set the desired BER minimum. It is then divided two ways in a 3 dB splitter. One output is injected into the optical receiver input and the other feeds a power meter which monitors the incident optical power. The regenerator input is now at the laser driver of the optical transmitter. This input is driven directly by the

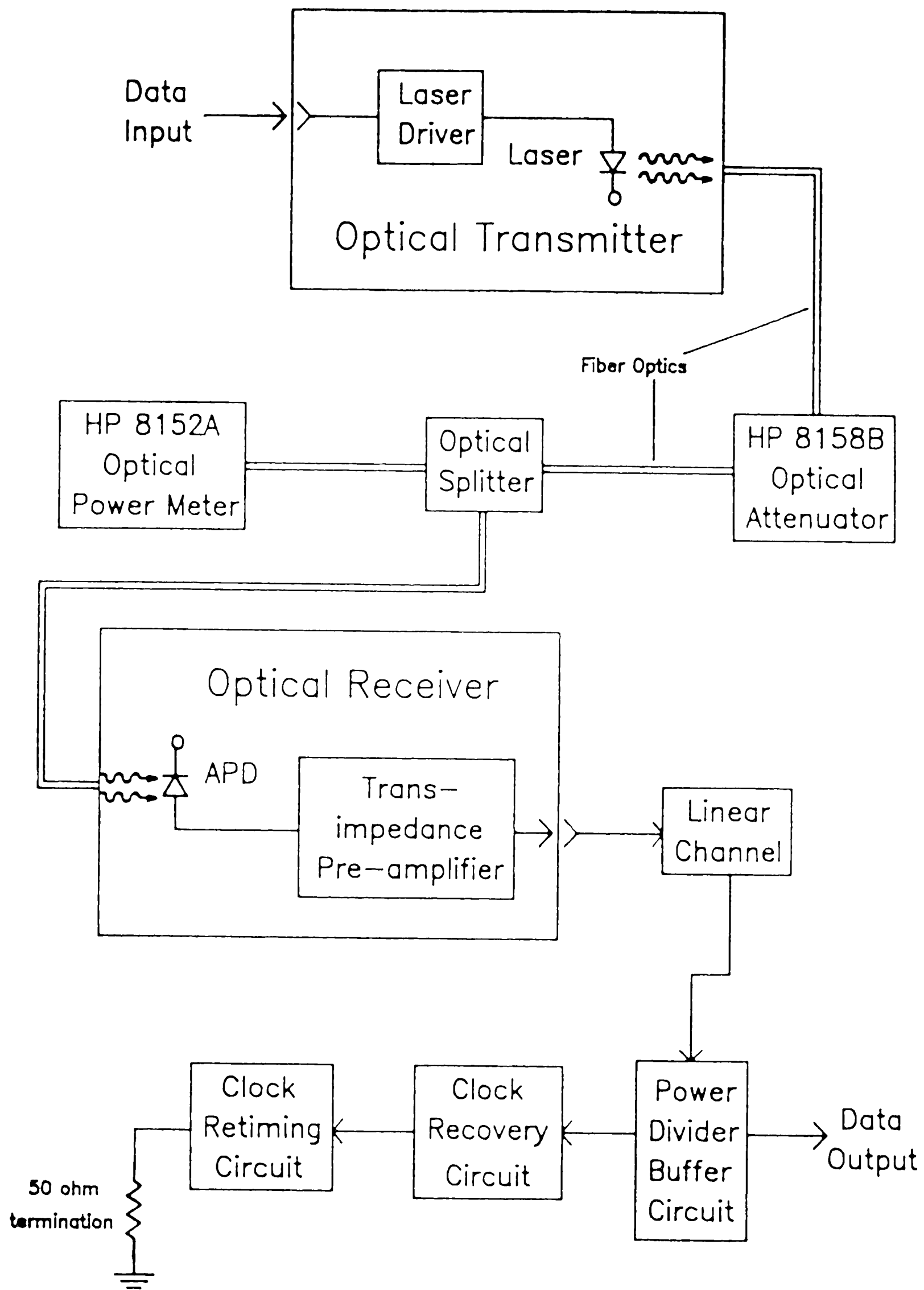


Fig. 4.2. Modified regenerator block diagram for BER measurement of decision circuit input.

Anritsu data generator.

The BER of the power divider output (decision circuit input) is measured by the Anritsu detector as well as the sampling technique. The overall regenerator test setup is shown in Fig. 4.3. It is the same basic circuit as that used in the gaussian measurement test system. The major difference is that the modified regenerator is used in the circuit in place of the digital/gaussian noise source. In addition, the bit rate is 1.7 Gb/s instead of 1.0 Gb/s which is used in the gaussian measurements.

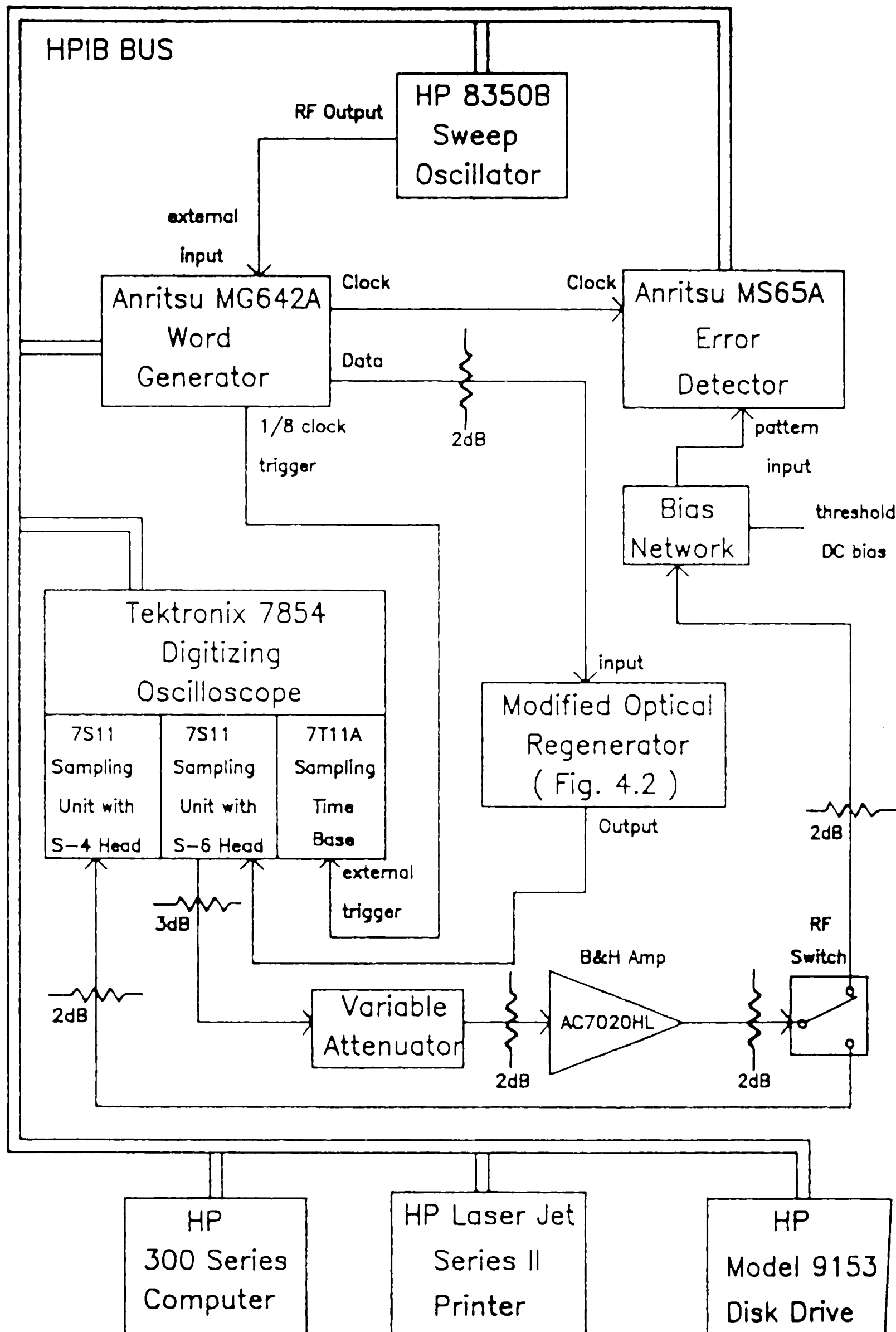


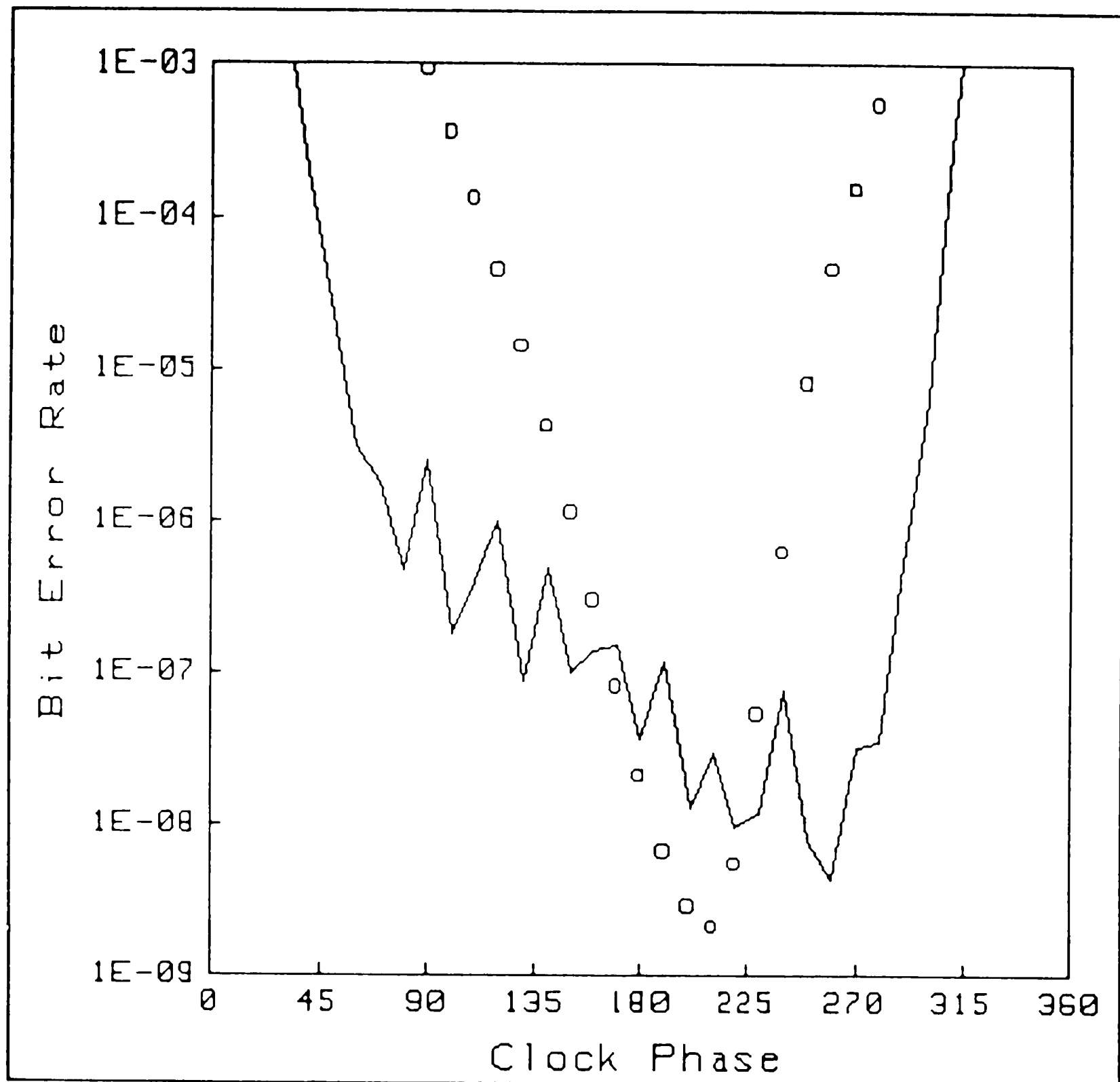
Fig. 4.3. Regenerator measurement test system.

Chapter 5 BER Measurement Results

Comparisons will now be made of BER measurements obtained using the Anritsu detector versus the predicted BERs computed using the sampling technique. The ideal gaussian waveforms will be evaluated first, followed by those of the optical regenerator. The BER will be measured and plotted as a function of clock phase. In this way, a comprehensive comparison is achieved across a wide spectrum of error rates instead of simply comparing them at a single phase such as at minimum BER.

5.1. Gaussian Experimental Results

The results of the initial gaussian measurements are typified by the BER curves in Fig. 5.1. Poor agreement between predicted and measured BER is evident in two aspects of the plot. First, the minimum BER predicted is expected to be the same or better than that measured, which is not the case. The calculations of the predicted curves are based on ideal performance whereas the detector measurements are made using actual circuitry which is degraded by lower order effects such as undesirable detector noise. The other major discrepancy in the plot is that the measured BER vs. phase curve



Anritsu measured BER = o
 Predicted BER using sample data = _____

Fig. 5.1. Initial plot of BER vs. clock phase for a gaussian waveform without filtering which exhibits a minimum BER of 2.1×10^{-9} at 1.7 Gb/s using a 2 Gb/s Anritsu system.

is much narrower than that predicted. The calculated curve predicts a phase margin of 205° at a BER of 1.0×10^{-6} whereas the measured curve is only 90° .

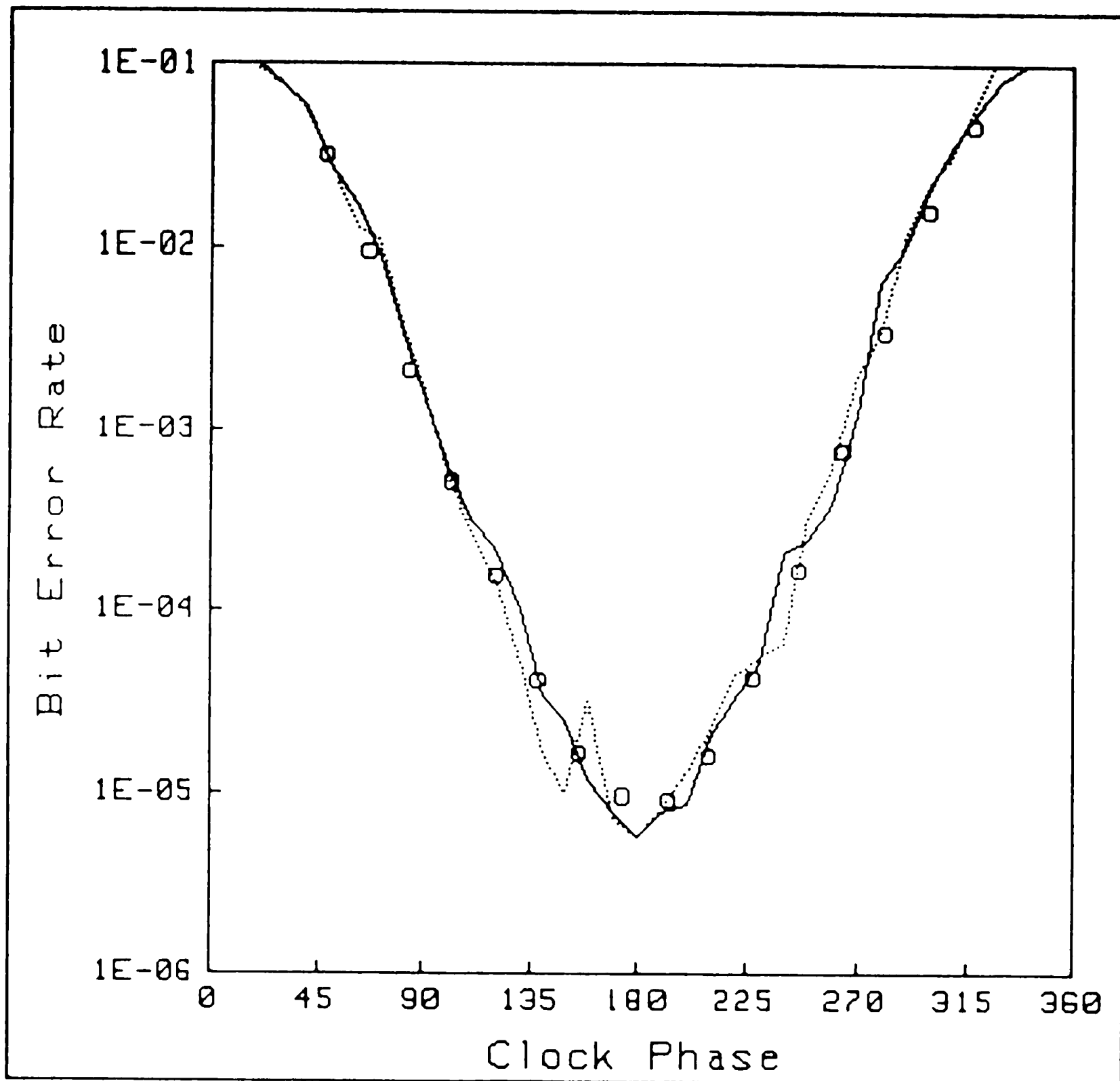
The discrepancies associated with the minimum BER in Fig. 5.1 are attributed to the different bandwidths of the error detector and the sampling oscilloscope. The oscilloscope samples noise impulses up to 14 GHz whereas the detector only passes signal frequencies to a few gigahertz. The predicted curve minimum is worse than that measured because the calculations via the scope include high frequency noise that the error detector tends to filter out. A 1.0 GHz low pass filter placed just in front of the RF switch, shown in Fig. 3.3, resolves this problem. The maximum frequency to each is therefore limited to 1.0 GHz to match the bandwidths.

The narrowed curve of the measured BER in Fig. 5.1 is partially attributed to the timing jitter and setup and hold times of the MS65A error detector. The combination of these effects and limited detector bandwidth results in a detector specification requiring an eye opening greater than 300pS. The overall result of these problems is to narrow the measured curve by as much as 75pS on each side. The Anritsu 3.0 Gb/s detector, which requires less eye opening, will be used instead to minimize these effects. Also, the bit rate will be

lowered to 1.0 Gb/s so that any remaining errors caused by this type of problem will be a smaller percentage of the pulse width. This in turn will be less error when expressed in terms of clock phase.

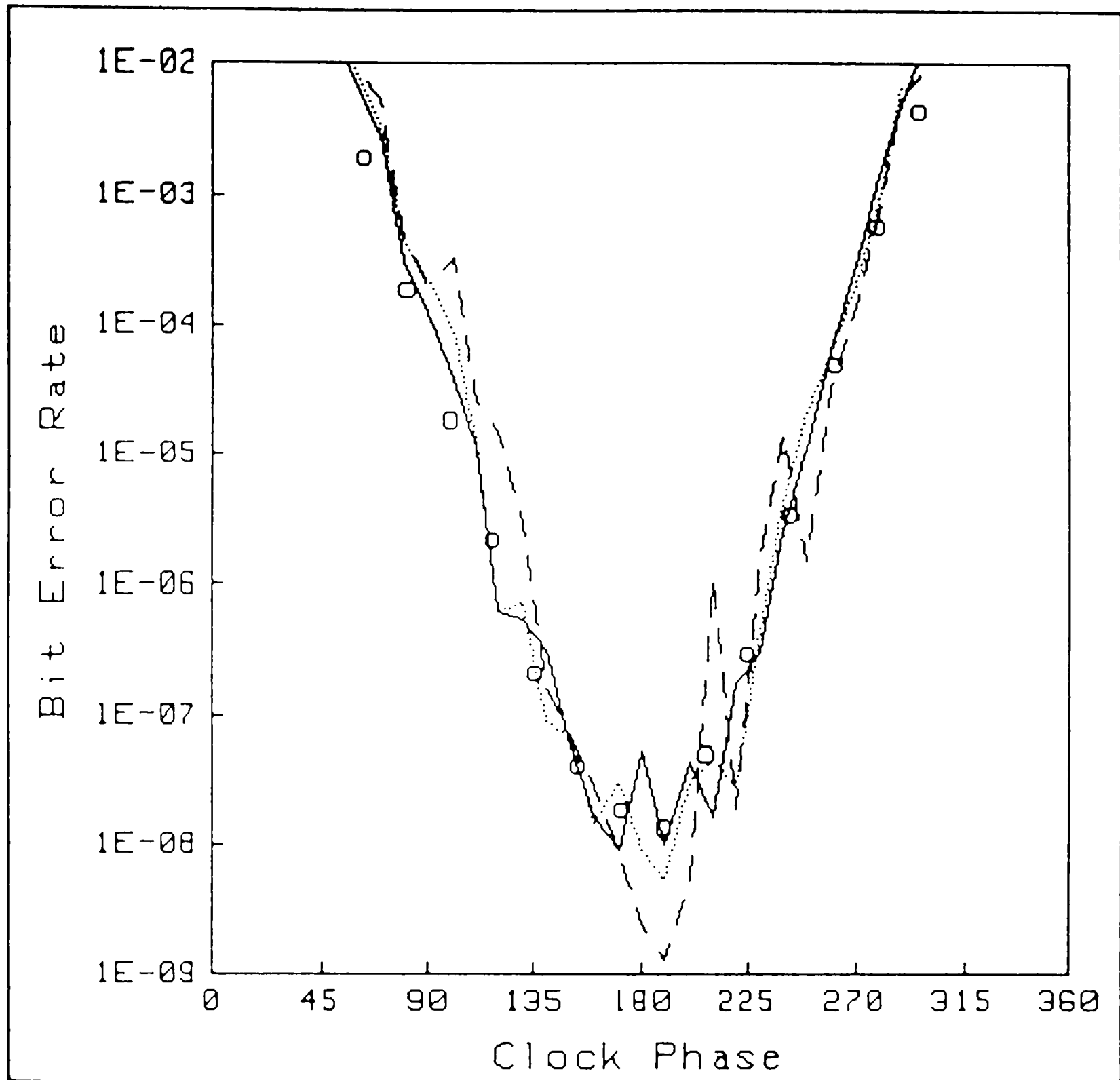
The plot shown in Fig. 5.2 is obtained by implementing the improvements suggested in the last two paragraphs. A minimum measured BER of 9.4×10^{-6} has been selected for this plot. The agreement between measured (circles) and predicted (solid line) is excellent. A second curve, indicated by the dotted line, has been included in Fig. 5.2 in order to demonstrate the repeatability of the measurements. This curve was generated using an independent sample and indicates extremely good repeatability.

Comparisons will also be made at additional BER minimums of 1.4×10^{-8} and 1.0×10^{-10} . This is necessary to check the dynamic range of measurement of the sampling technique. The BER = 1.4×10^{-8} plot is depicted in Fig. 5.3. Good agreement is evident once again between the predicted and measured curves. Additional curves have been added to Fig. 5.3 using sample sizes of 500 and 100 to determine the minimum sample size requirements. The 500 sample curve (dotted line) is still relatively good. The 100 sample curve (dashed line) shows poor BER minimum agreement and degraded repeatability, especially along



Anritsu measured BER = o
 Predicted BER using original sample = _____
 Predicted BER using a second sample =

Fig. 5.2. A plot of BER vs. clock phase for a gaussian waveform with a 1.0 Ghz filter. The minimum BER is 9.4×10^{-6} at 1.0 Gb/s using a 3 Gb/s Anritsu system.



Anritsu measured BER = o

Predicted BER using orig. sample (900 points) = _____

Predicted BER using 500 points of same sample =

Predicted BER using 100 points of same sample = - - - - -

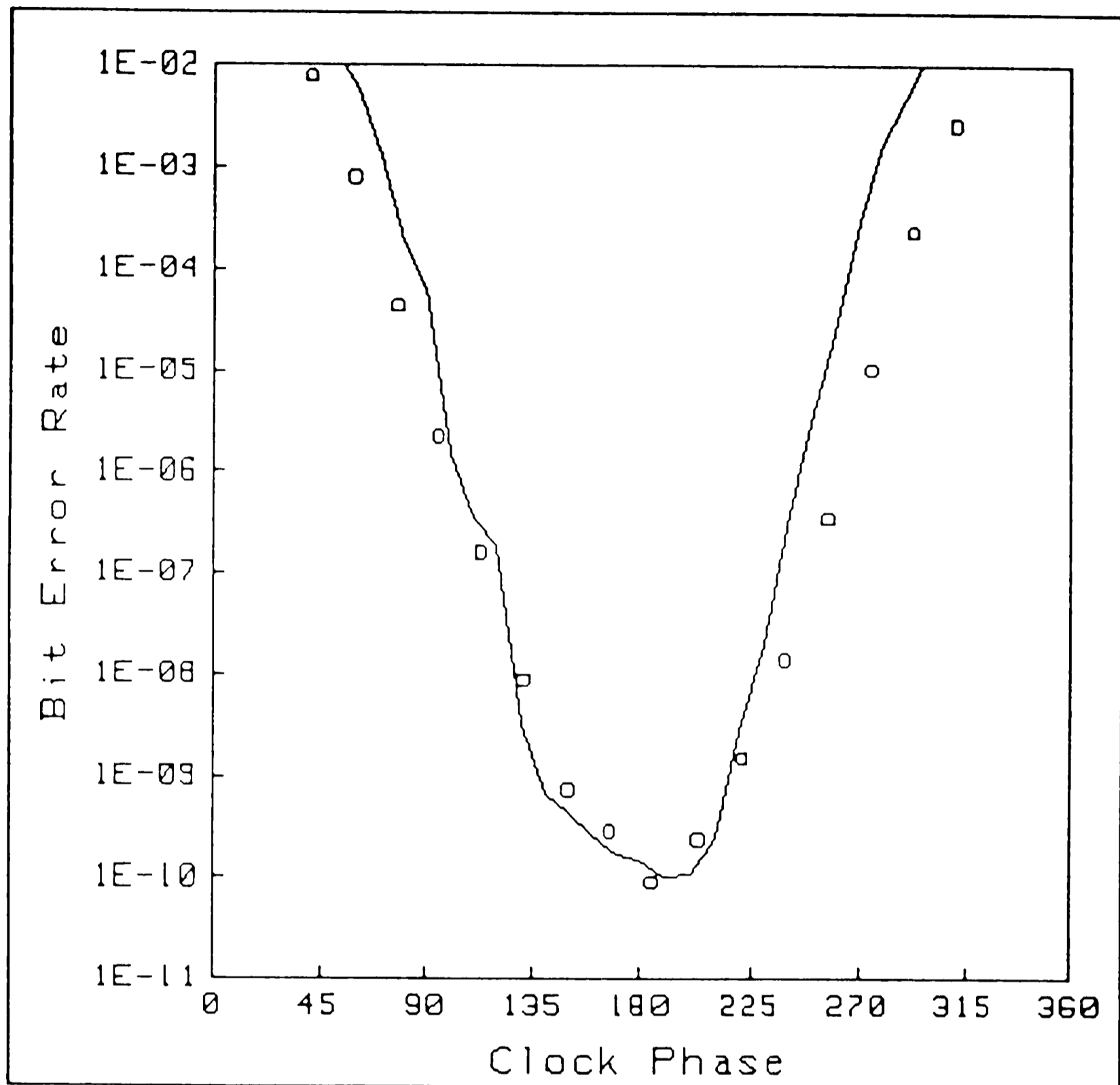
Fig. 5.3. A plot of BER vs. clock phase for a gaussian waveform with a 1.0 Ghz filter using multiple sample sizes. The minimum BER is 1.4×10^{-8} at 1.0 Gb/s using a 3 Gb/s Anritsu system.

the jagged sidewalls of the curve. These results dictate sample sizes of at least 500 samples for quality measurements.

The BER = 1.0×10^{-10} minimum is shown in Fig. 5.4. The BER minimums agree almost exactly. Some error is evident in the narrowing of the calculated curve however it is not much considering that the measurements span eight orders of magnitude. BER measurements less than 1.0×10^{-10} will not be pursued since so few errors occur that it would require many hours to characterize a single waveform with the error detector.

5.2. Regenerator Experimental Results

The regenerator BER measurements were made using a 1.5 Ghz low pass filter in place of the 1.0 Ghz filter used for the gaussian testing. This filter serves an additional purpose other than the bandwidth matching function described in Section 5.1. The optical power in the link (about 10 feet long) is varied using pure attenuation instead of adding or subtracting lengths of fiber. The optical dispersion will therefore be much less than that typically caused by kilometers of fiber. The filter tends to help simulate the dispersive effects of long regenerator links by degrading the edge speeds



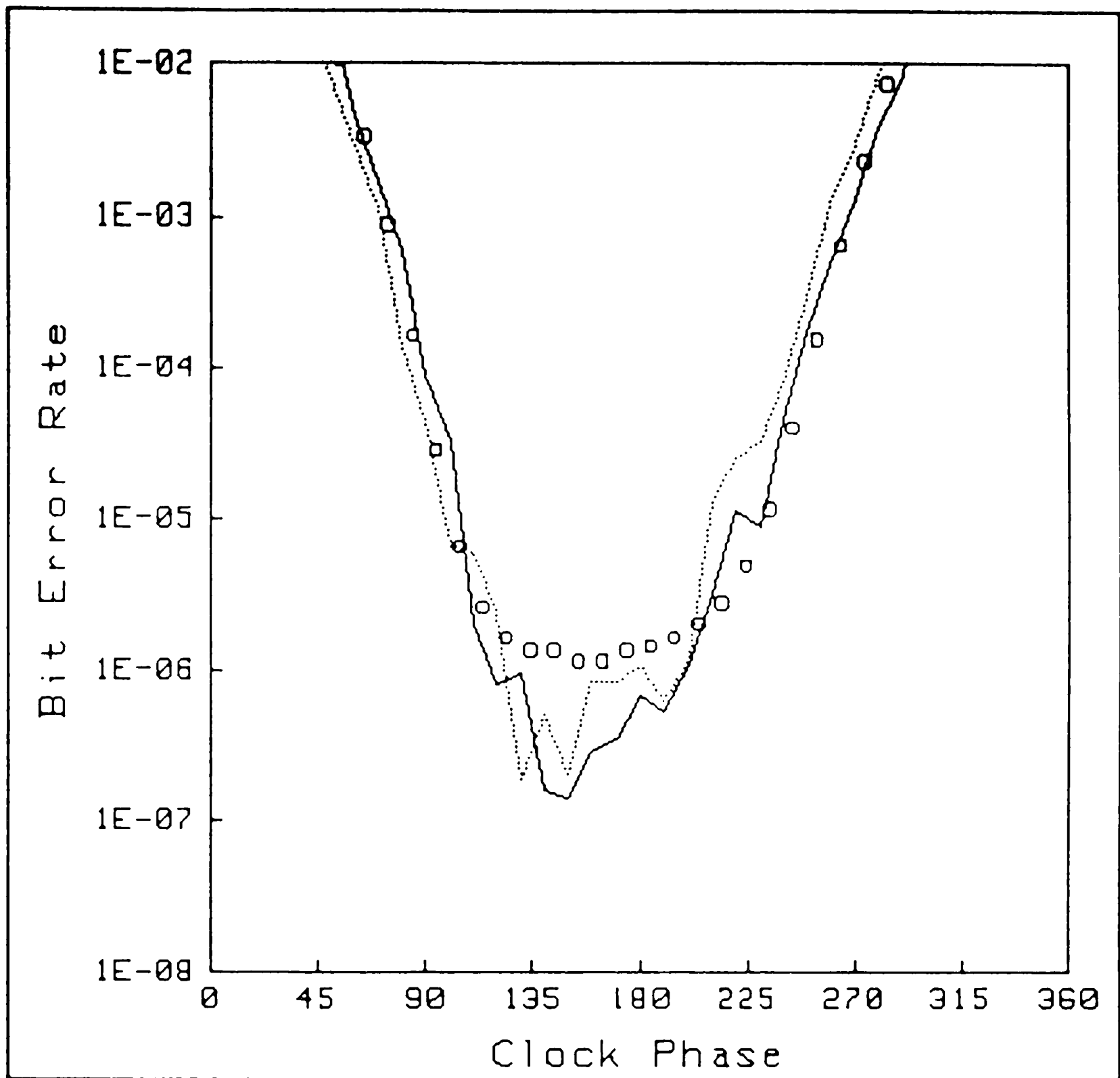
Anritsu measured BER = o
 Predicted BER using sample data = _____

Fig. 5.4. A plot of BER vs. clock phase for a gaussian waveform with a 1.0 Ghz filter. The minimum BER is 1.0×10^{-10} at 1.0 Gb/s using a 3 Gb/s Anritsu system.

and thereby creating a more realistic system model.

BER curves are generated in a similar fashion as that done for the gaussian measurements. A plot of BER vs. clock phase is shown in Fig. 5.5 for a waveform which exhibits a BER minimum of 1.0×10^{-6} . Agreement between the measured (circles) and predicted (solid line) curves is good except at low bit error rate. The predicted BER curve from a second sample set (plotted using dotted line) shows good repeatability with the original curve (solid line). The measured BER curve tends to flatten out at the bottom whereas the predicted curve is lower. This discrepancy is partially attributed to the measuring error in the MS65A error detector associated with the 300 pS eye opening requirement as described in Section 5.1.

The fact that a gaussian model is being used to characterize the regenerator signals, which are not purely gaussian, also contributes to the discrepancies. In addition to the gaussian noise sources within the regenerator, the statistics associated with optical signal tend to be poisson in nature [7]. Still other noise sources such as the avalanche process associated with the APD diode in the receiver are characterized by functions which are not easily expressed in simple analytical form. Fortunately, the gaussian equations used to describe these phenomena are a fair approximation

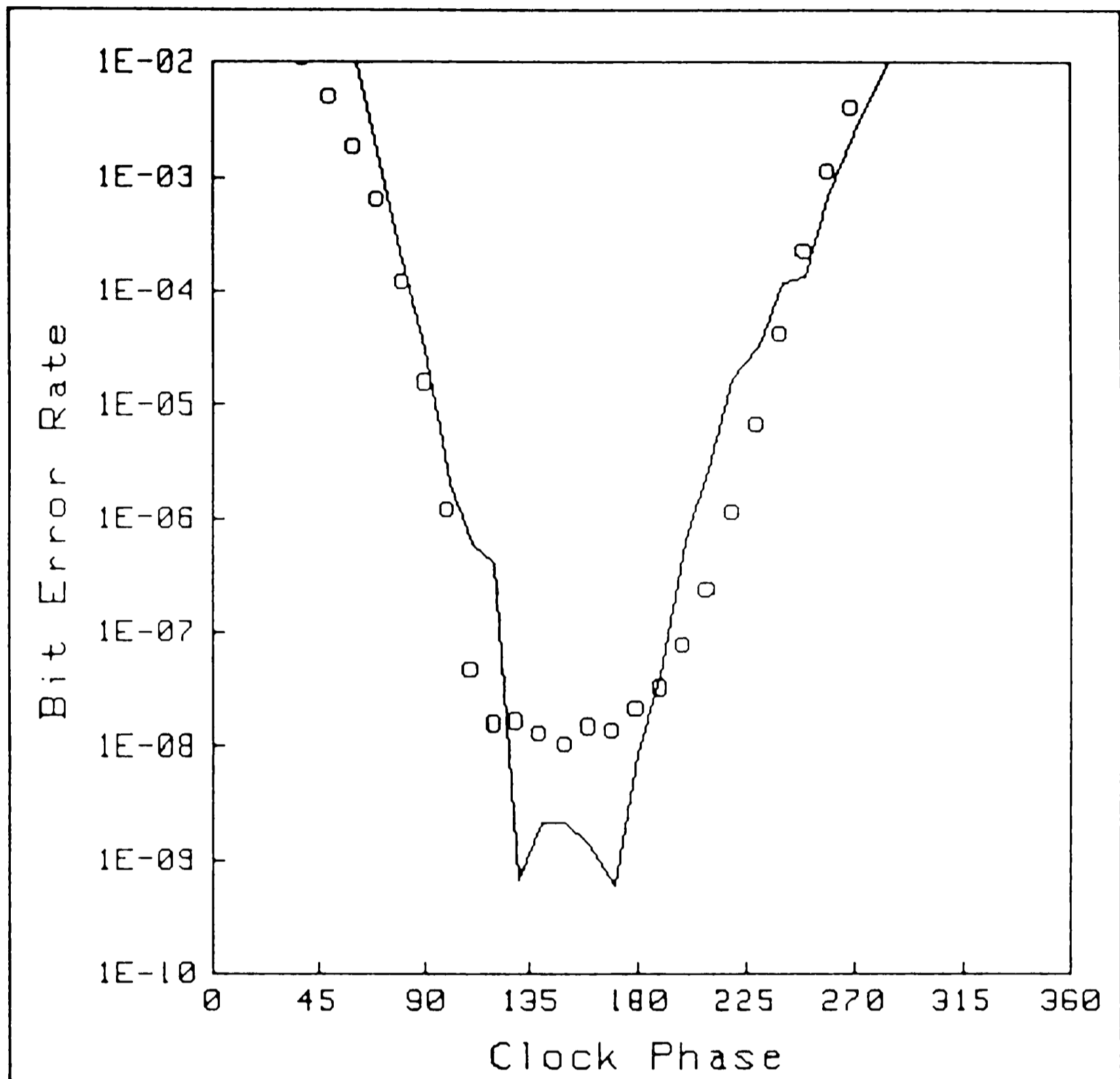


Anritsu measured BER = o
 Predicted BER using original sample = —————
 Predicted BER using a second sample =

Fig. 5.5. A plot of BER vs. clock phase for a regenerated waveform with a 1.5 GHz filter. The minimum BER is 1.0×10^{-6} at 1.7 Gb/s using a 2 Gb/s Anritsu system.

to the actual equations. This is proven by the central-limit theorem [11] which states that the sum of a large number of independent random variables tends to a gaussian distribution.

A second BER plot is generated for a waveform which exhibits a BER minimum of 1.0×10^{-8} . This is depicted in Fig. 5.6. Once again flattening of the measured curve is evident at low bit error rate. Discrepancies at this point indicate predicted BERs which are an order of magnitude, in the worst case, better than those measured.



Anritsu measured BER = ○
 Predicted BER using original sample = —

Fig. 5.6. A plot of BER vs. clock phase for a regenerated waveform with a 1.5 Ghz filter. The minimum BER is 1.0×10^{-8} at 1.7 Gb/s using a 2 Gb/s Anritsu system.

Chapter 6 Conclusions and Future Extensions

This thesis is concerned with the development of a new bit error rate measurement technique applicable to high frequency baseband digital signals.

The technique developed assumes that all noise contributions in the system are purely gaussian and uses probabilistic ideas in order to determine the BER. Implementation of this technique is achieved by utilizing a relatively inexpensive digitizing oscilloscope to capture the data and some computing equipment to process it.

Tests were set up to compare results obtained using this technique with those from a commercial error detector. Both gaussian and optically regenerated signals with a wide variety of S/N ratios were evaluated to determine the BER vs. clock phase relationship at the optimal threshold level. It was found that a filter is necessary in order to match the bandwidth of the digitizing oscilloscope to that of the error detector. With the filter in place, the results obtained for pure gaussian signals showed excellent agreement between measured and predicted BERs. When the signal is from an optical regenerator, the greatest discrepancy between the two was of an order in magnitude. Some of this

difference is attributed to the error detector itself and can be reduced with a detector which has improved eye opening characteristics. This agreement confirms the assumption that the non-gaussian regenerator phenomena, such as poisson statistics in the optics, are well approximated by gaussian theory, as implied by the central-limit theorem.

However, the regenerator results could be further improved by developing more accurate equations, as done in Chapter 2, which take into account the regenerator noise statistics.

A limitation of the sampling system, as implemented, is the speed at which it can digitize and transfer data to the computer. It typically took about 15 minutes to acquire 900 valid samples at 36 phases (32,400 points). This situation could be greatly improved if a dedicated interface which incorporates flash A/D converters under microprocessor control was constructed and used instead.

The applications of the technique developed are not limited to the determination of BER vs. clock phase which has been demonstrated in this thesis. The same BER measurement technique can be used to generate information about BER vs. threshold level at a fixed phase or to provide phase margin or eye margin measurements. In addition, the optical sensitivity of the regenerator can

be derived by performing a linear regression of BER vs. optical power.

Appendix A Sampling and BER Calculations Software

Appendix A contains the BASIC software developed during the course of this thesis in order to implement the measurement concepts described in Chapter 3.

```

1      !*****
2      ! RE-STORE"T_WEF_BER< >:CS80,702,1"
3      ! LATEST SOFTWARE UPDATE-- 7/14/88 (08:46 AM)
4      !*****
5      !
6      Ber_test
7      END
8      !
9      !*****
10     SUB Ber_test ! T_WEF MAIN LOOP
11     !*****
12     OPTION BASE 1
13     ! WRITTEN BY W.E.FULMER - 11/20/86
14     ! PROGRAM DIGITIZES TEK7854(W/ 7S11,7T11 PLUG-INS)
15     ! DATA POINTS ARE TRANSFERRED TO 9836, STORED IN AN ARRAY AND PLOTTED
16     ! POINTS ARE GRAPHED AMPLITUDE RANGE VS. OCCURENCE
17     ! SENSITIVITY IS THEN CALCULATED FROM THE GAUSSIAN NATURE OF THE POINT
18     ! DISTRIBUTION.
19     COM /Wave/ Wave$(8000),Wavehead$(130),Dig_array(1080),X_plot(1080),Y_plot(
20     1080)
21     COM /T/ T_point(1030)
22     COM /Dig/ V_1,V_0,Vmiddle,Occur_ampl(1:2000),Total_cells,D,Vsamp_size,Valid_samp(0:35,0:920),Cell_0,Cell_1,Ber,Phs
23     COM /Hpib/ Tek1,Tek2,Tek3,Tek4,Tek5,Tek6,Tek7,Tek8,Tek9,Hard_disk,Atten_driv,Scope,Freq_ct,Opt_pm,Opt_atten,Sweep_osc,Data_acq,Anr_ber,Anr_prog,Tek_ct
24     COM /Pp/ Printing,Comment$(60)
25     COM /Dstorm/ P_w,Xzero,Xmult,Xun$(10),Yzero,Ymult,Yun$(10)
26     COM /Zip/ Subset_len,Subset_pt(100),Valid_pt(100),Samp_count(0:35),Unfill_ct,Bin_pt(100)
27     COM /Curs/ INTEGER X_over1,X_over2
28     COM /Sav/ Filenam$(10),Choice$(1)
29     COM /Sig/ Best_fit_0(10),Best_fit_1(10),Sigma_0(10),Sigma_1(10),Unoccur_0,Unoccur_1,P_0(10),P_1(10),P_e(10),Q_0(10),Q_1(10)
30     COM /Vvv/ Vmin,Vmax,Vspan,Vcell
31     COM /Strait/ Vsamp_ave,Sig_0,Sig_1,V0_count,V1_count,V0_ave,V1_ave,V_zero,V_one,Q_zero(0:35),Q_one(0:35),P_zero(0:35),P_one(0:35),P_error(0:35)
32     ! UNOCCUR=UNNORMALIZED OCCURRENCES AT V_0 OR V_1
33     DIM Heading$(25)
34     Start: !
35     GINIT
36     PRINTER IS 1
37     PRINT CHR$(12)
38     GRAPHICS ON
39     GCLEAR
40     I=0
41     Scope=708
42     Data_acq=709
43     Atten_driv=702
44     PRINT TABXY(1,1)," ENTER ADDRESS OF PRINTER DESIRED(701 OR 26)"
45     INPUT Printing
46     DUMP DEVICE IS Printing
47     PRINT TABXY(1,1)," "
48     CSIZE 4

```

```

48 PRINT TABXY(11,5)," ENTER FILENAME TO BE USED FOR DATA STORAGE "
49 PRINT TABXY(11,7)," OR RETRIEVAL -(ex. SAMPLE15)"
50 INPUT "FILENAME=?",Filename$
51 PRINT CHR$(12);
52 PRINT TABXY(11,5)," ENTER A DESCRIPTIVE COMMENT "
53 INPUT Comment$
54 PRINT CHR$(12);
55 PRINTER IS Printing
56 Esc$="
57 PRINT Printing;Esc$&"&l80" | 8 LINES PER INCH
58 PRINT Printing;Esc$&"&a25L" | LEFT MARGIN= COLUMN 25
59 PRINT Printing;Esc$&"(s16.66H" | COMPRESSED
60 PRINT Printing;Esc$&"*t100R" | MINIATURIZE GRAPHICS
61 PRINT CHR$(12);
62 PRINT "Data File Description- ";Comment$
63 PRINT "DATE=";DATE$(TIMEDATE)," TIME=";TIME$(TIMEDATE)
64 PRINT
65 PRINT "Data Storage Filename-";Filename$
66 PRINT
67 PRINTER IS 1
68 Bak: |
69 CSIZE 4
70 MOVE 15,65
71 LABEL "ENTER ""N"" TO CREATE A NEW VALID SAMPLE"
72 MOVE 15,50
73 LABEL "ENTER ""S"" TO CALCULATE P(E) USING STORED DATA"
74 INPUT "Selection=?",Choice$
75 GCLEAR
76 IF Choice$="N" OR Choice$="n" THEN GOTO New_data
77 IF Choice$="S" OR Choice$="s" THEN
78 MASS STORAGE IS ":CS80,700,1"
79 ASSIGN @Path_1 TO Filename$
80 ENTER @Path_1;Vsamp_size,Ber,Xmult,Ymult,Yzero,P_w
81 REDIM Valid_samp(0:35,1:Vsamp_size)
82 ENTER @Path_1;Valid_samp(*)
83 ASSIGN @Path_1 TO * | CLOSSES I/O PATH
84 Vsamp_size=50
85 DIM Tv_samp(0:35,1:920)
86 REDIM Tv_samp(0:35,1:Vsamp_size)
87 FOR X=0 TO 35
88 FOR Y=1 TO Vsamp_size
89 Tv_samp(X,Y)=Valid_samp(X,Y)
90 NEXT Y
91 NEXT X
92 REDIM Valid_samp(0:35,1:Vsamp_size)
93 MAT Valid_samp= Tv_samp
94 PRINT TABXY(10,10),"DO YOU WISH ALL TEST DATA? (Y or N)"
95 PRINTER IS Printing
96 PRINT "Sample Size=";Vsamp_size,"BER=";Ber
97 PRINT "Xmult=";Xmult,"Ymult=";Ymult,"Yzero=";Yzero,"P_w=";P_w
98 INPUT D$
99 IF D$="Y" THEN
100 FOR Phs=0 TO 35
101 Phase=DROUND(Phs*10,3)
102 PRINT "*****
*****"
103 PRINT " PHASE = ";Phase;" Degrees"
104 PRINT "*****
*****"
105 FOR Jx=1 TO Vsamp_size
106 PRINT "PT#";Jx;"=";Valid_samp(Phs,Jx),
107 NEXT Jx
108 NEXT Phs
109 END IF
110 PRINTER IS 1
111 Total_cells=100 | ASSUME FOR PREVIOUSLY STORED DATA
112 REDIM Occur_ampl(1:Total_cells)

```

```

113     GOTO Occur_master
114     END IF
115     GOTO Bak      I RE-ENTER CHOICES
116 New_data: Total_cells=100      I DIVIDES THE V SPAN INTO 100 EQUAL CELLS
117     REDIM Occur_ampl(1:Total_cells)
118     CSIZE 4
119     MOVE 10,50
120     LABEL "ENTER THE DESIRED SAMPLE SIZE(1-2000)"
121     INPUT Vsamp_size
122     PRINTER IS Printing
123     PRINT "VALID SAMPLE SIZE=";Vsamp_size
124     PRINTER IS 1
125     GCLEAR
126     CSIZE 5
127     MOVE 10,65
128     LABEL "ADJUST SENSITIVITY TO THE DESIRED BER"
129     MOVE 10,50
130     LABEL "SWITCH FROM SCOPE TO RCVR AS REQUIRED"
131     PRINTER IS 1
132     PRINT TABXY(20,50);"ENTER THE BER ACHIEVED!- ( ex. 2.5E-9 )"
133     INPUT "BER=?";Ber
134     PRINTER IS Printing
135     PRINT "BER=";Ber
136     PRINTER IS 1
137     PRINT CHR$(12)
138     SYSTEM PRIORITY 0
139     OFF KEY
140     !-----
141     !THIS SECTION ACQUIRES THE SAMPLE POPULATION FOR THE ERROR CALCULATIONS
142     !-----
143     CALL Data_storm("5 1 2 >P/W","ACQ",0)
144     PRINTER IS Printing
145     PRINT
146     PRINT "COMMENTS- ";Comment$
147     PRINT
148     PRINT "          POINTS PER WAVEFORM= ";P_w
149     PRINT "          Xoffset= ";Xzero
150     PRINT "          Xmultiplier= ";Xmult
151     PRINT "          Xunits= ";Xun$
152     PRINT "          Yoffset= ";Yzero
153     PRINT "          Ymultiplier= ";Ymult
154     PRINT "          Yunits= ";Yun$
155     PRINT
156     PRINT
157     PRINTER IS 1
158     CALL Cursor
159     CALL Samp_builder I ACQUIRES VALID_SAMP(*) FROM SUCCESSIVE WAVEFORMS
160     CALL Samp_saver  I STORES VALID_SAMP(*) ON DISK
161     GOTO Start
162     !-----
163     !THIS SECTION BUILDS AND PLOTS OCCURRENCE VS CELL# FOR EACH OF THE
164     !PHASE SAMPLE SETS
165     !-----
166 Occur_master: I
167     PRINTER IS 1
168     GCLEAR
169     PRINT TABXY(5,10),"ENTER ""M"" FOR MANUAL SELECTION OF V_1,V_0"
170     PRINT TABXY(5,8),"ENTER ""A"" FOR AUTO SELECTION OF V_1,V_0"
171     INPUT Gate$
172     IF Gate$="M" OR Gate$="m" THEN
173         Selector=1 I MANUAL
174         GOTO Brick
175     END IF
176     IF Gate$="A" OR Gate$="a" THEN
177         Selector=2 I AUTO
178         GOTO Brick
179     END IF

```

```

180          GOTO Occur_master
181 Brick: 1
182      DIM Xax$(25),Yax$(25),Title$(45),Phs$(25)
183      Xax$="Voltage cells"
184      Yax$="Number of Occurrences"
185      |-----|
186      | THIS SECTION FINDS Vmin ERROR FOR 180 DEGREES PHASE SUBSET
187      |-----|
188      Phs=18
189      Occur_builder(Selector)
190      V_zero=V_0
191      V_one=V_1
192      Gc_sigma(1)
193      PRINTER IS Printing
194      PRINT
195      PRINT "PROBABILITY OF ERROR USING MAXIMAL OCCUR 1&0 (180 DEGREE PHASE)"
196      PRINT
197      PRINT " Vthreshold          Q_zero          Q_one          BER"
198      Ber_min=1
199      FOR Jib=1 TO 999
200      D=V_zero+(V_one-V_zero)/1000*Jib
201      Prob_error(0) ! NO PRINTING
202      IF FRACT(Jib/20)=0 THEN PRINT D;TAB(20);Q_zero(Phs);TAB(35);Q_one(Phs);T
AB(50);P_error(Phs)
203      IF P_error(Phs)<Ber_min THEN
204          Dmin_mo=D
205          Ber_min=P_error(Phs)
206      END IF
207      NEXT Jib
208      PRINT
209      PRINT "D threshold optimal=";Dmin_mo,"BER minimum=";Ber_min
210      PRINT CHR$(12);
211      V_zero=V0_ave
212      V_one=V1_ave
213      Gc_sigma(1)
214      PRINTER IS Printing
215      PRINT
216      PRINT "PROBABILITY OF ERROR USING V_0,1average (180 DEGREE PHASE)"
217      PRINT
218      PRINT " Vthreshold          Q_zero          Q_one          BER"
219      Ber_min=1
220      FOR Jib=1 TO 999
221      D=V_zero+(V_one-V_zero)/1000*Jib
222      Prob_error(0) ! NO PRINTING
223      IF FRACT(Jib/20)=0 THEN PRINT D;TAB(20);Q_zero(Phs);TAB(35);Q_one(Phs);T
AB(50);P_error(Phs)
224      IF P_error(Phs)<Ber_min THEN
225          Dmin_ave=D
226          Ber_min=P_error(Phs)
227      END IF
228      NEXT Jib
229      PRINT
230      PRINT "D threshold optimal=";Dmin_mo,"BER minimum=";Ber_min
231      Error_opt=1
232      FOR Phs=0 TO 35 STEP 3
233      Occur_builder(Selector) !BUILDS OCCUR. VS. RANGE USING SELECTOR CHOSEN
234      PRINTER IS 1
235      CALL Gc_sigma(1) ! CALCULATES SIGMA 1&0 BASED ON SAMPLE STATISTICS
236      PRINTER IS Printing
237      PRINT
238      PRINT "PROBABILITY OF ERROR USING V_ZERO,ONE=V_0,1(MAXIMAL OCCUR.)"
239      PRINTER IS 1
240      V_zero=V_0
241      V_one=V_1
242      D=Dmin_mo
243      CALL Prob_error(1) ! CALC. PROB. OF ERROR GIVEN SIGMA0,SIGMA1, AND D
244      PRINTER IS Printing

```

```

245 GOSUB Djammer
246 PRINTER IS Printing
247 PRINT
248 PRINT "PROBABILITY OF ERROR USING V_ZERO,ONE=V0_AVE,V1_AVE"
249 PRINTER IS 1
250 V_zero=V0_ave
251 V_one=V1_ave
252 D=Dmin_ave
253 CALL Prob_error(1)
254 PRINT
255 GOSUB Djammer
256 PRINT
257 IF Ber_min<Error_opt THEN
258     Error_opt=Ber_min
259     D_opt=Dmin
260 END IF
261     PRINTER IS 1
262     Phs$=VAL$(10*Phs)
263     Phs$=" @"&Phs&&" degrees phase"
264     Title$="VOLTAGE DISTRIBUTION"&Phs$
265     Ymax=MAX(Occur_ampl(*))
266     IF Ymax<50 THEN Ymax=50
267     Wef_plot(Total_cells,Ymax,Xax$,Yax$,Title$,Occur_ampl(*)!PLOT OCCUR vs C
ELL
268     GCLEAR
269 NEXT Phs
270 PRINTER IS Printing
271 PRINT CHR$(12);
272 D=D_opt
273 PRINT "          Dopt=";D
274 PRINT
275 PRINT "PROB. OF ERROR USING Dopt from best phase/ V_0,V_1 RECALC. AT EACH
PHASE"
276 PRINT "Phase(deg)   Q(ZERO)       Q(ONE)       P(ZERO)       P(ONE)
P(ERROR)"
277 PRINT
278 FOR Phs=0 TO 35
279 Phase=Phs*10
280 Gc_sigma(0)
281 V_one=V1_ave
282 V_zero=V0_ave
283 Prob_error(0)
284 PRINTER IS Printing
285 PRINT Phase;TAB(12);Q_zero(Phs);TAB(28);Q_one(Phs);TAB(42);P_zero(Phs);TA
B(57);P_one(Phs);TAB(69);P_error(Phs)
286 PRINTER IS 1
287 NEXT Phs
288 PRINTER IS Printing
289 PRINT CHR$(12);
290 GOTO 307
291 PRINTER IS 1
292 Djammer:  IJAMS D FROM V_0 TO V_1 GIVEN SIGMA,V_0,1
293     Ber_min=1
294     FOR Jib=1 TO 999
295     D=V_zero+(V_one-V_zero)/1000*Jib
296     Prob_error(0) ! NO PRINTING
297     IF P_error(Phs)<Ber_min THEN
298         Dmin=D
299         Ber_min=P_error(Phs)
300     END IF
301     NEXT Jib
302 PRINTER IS Printing
303 PRINT "D threshold optimal=";Dmin,"BER minimum=";Ber_min
304 PRINTER IS 1
305 RETURN
306 !
307 ! MAIN PROGRAM END

```



```

308 SUBEND
309 |*****
310 |*****
311 | THIS IS THE END OF THE MAIN PROGRAM
312 |*****
313 |*****
314 |
315 |*****
316 SUB Cursor          | WAVEFORM MUST BE IN SCOPE MEMORY
317                   | ACQUIRES LEFT AND RIGHT (1&2) CROSSOVERS
318                   | UNITS ARE IN POINTS
319 |*****
320 COM /Hpib/ Tek1,Tek2,Tek3,Tek4,Tek5,Tek6,Tek7,Tek8,Tek9,Hard_disk,Atten_dr
iv,Scope,Freq_ct,Opt_pm,Opt_atten,Sweep_osc,Data_acq,Anr_ber,Anr_prog,Tek_ct
321 COM /Pp/ Printing,Comment$
322 COM /Curs/ INTEGER X_over1,X_over2
323   COM /Dstorm/ P_w,Xzero,Xmult,Xun$,Yzero,Ymult,Yun$
324 Freez:   !
325   PRINTER IS 1
326   OUTPUT Scope;"STORED DOT"
327   OUTPUT Scope;"CRS2-1"          ! CURSOR #1 AND 2 ON
328   LOCAL 7
329   PRINT "SET CURSOR 1 TO LEFT CROSSOVER AND CURSOR 2 TO RIGHT CROSSOVER "
330   PRINT
331   PRINT " PRESS CONTINUE WHEN READY"
332   PAUSE
333   REMOTE 7
334   LOCAL LOCKOUT 7
335   OUTPUT Scope;"CRS1 HCRD SENDX"          ! SENDS LOCATION OF CURSOR#1
336   ENTER Scope;X_over1$
337   X_over1=(VAL(X_over1$))/Xmult          ! CONVERTS TO CURSOR#1 PT.#
338   PRINTER IS Printing
339   PRINT "LEFT CROSSOVER PT. OCCURS AT PT.#";X_over1
340   OUTPUT Scope;"CRS2-1 HCRD SENDX"          ! SENDS DELTA CURSOR #2-#1
341   ENTER Scope;X_over2$
342   X_over2=X_over1+(VAL(X_over2$))/Xmult          !CONVERTS TO CURSOR #2 PT.#
343   PRINT "RIGHT CROSSOVER PT. OCCURS AT PT.#";X_over2
344   Sub_center=(X_over1+X_over2)/2
345   PRINT " PHASE CROSSOVER CENTER OCCURS AT PT.#";Sub_center
346   PRINTER IS 1
347   IF ABS(X_over2-X_over1)<100 THEN
348     PRINT "LESS THAN 100 POINTS BETWEEN CROSSOVERS"
349     GOTO Freez
350   END IF
351   PRINT CHR$(12)
352 SUBEND
353 |
354 |*****
355 SUB Samp_saver      | THIS SUBPROGRAM STORES VALID_SAMP(*) ON DISK
356 |*****
357   COM /Zip/ Subset_len,Subset_pt(*),Valid_pt(*),Samp_count(*),Unfill_ct,Bi
n_pt(*)
358   COM /Dig/ V_1,V_0,Vmiddle,Occur_ampl(*),Total_cells,D,Vsamp_size,Valid_s
amp(*),Cell_0,Cell_1,Ber,Phs
359   COM /Sav/ Filenam$,Choice$
360   COM /Dstorm/ P_w,Xzero,Xmult,Xun$,Yzero,Ymult,Yun$
361   |
362   MASS STORAGE IS ":CS80,700,1"
363   F_size=(8*Vsamp_size)+100  ! ADD'L 100 BYTES ADDED
364   CREATE BDAT Filenam$,36,F_size !CREATES 36 RECORDS,W/(8*Vsamp_size)+100
bytes
365   ASSIGN @Path_1 TO Filenam$      ! OPENS I/O PATH TO FILE
366   OUTPUT @Path_1;Vsamp_size,Ber,Xmult,Ymult,Yzero,P_w
367   OUTPUT @Path_1;Valid_samp(*)
368   ASSIGN @Path_1 TO *              ! CLOSSES I/O PATH
369   PRINTER IS 1
370   PRINT TABXY(1,2),"DATA STORAGE COMPLETE"

```

```

371   WAIT 4
372   SUBEND
373   |*****
374   SUB Samp_builder
375   |*****
376   |***   BUILDS A VALID SAMPLE OF POINTS AT 36 EQUIDISTANT CLOCKING PHASES
377   |-----
378   |   SUBSET_LEN MUST BE ODD!!
379   |   COM /Wave/ Wave$,Wavehead$,Dig_array(*),X_plot(*),Y_plot(*)
380   |   COM /Zip/ Subset_len,Subset_pt(*),Valid_pt(*),Samp_count(*),Unfill_ct,Bi
n_pt(*)
381   |   COM /Dig/ V_1,V_0,Vmiddle,Occur_ampl(*),Total_cells,D,Vsamp_size,Valid_s
amp(*),Cell_0,Cell_1,Ber,Phs
382   |   COM /Curs/ INTEGER X_over1,X_over2
383   |   COM /Hpib/ Tek1,Tek2,Tek3,Tek4,Tek5,Tek6,Tek7,Tek8,Tek9,Hard_disk,Atten_
driv,Scope,Freq_ct,Opt_pm,Opt_atten,Sweep_osc,Data_acq,Anr_ber,Anr_prog,Tek_ct
384   |   COM /Pp/ Printing,Comment$
385   |   REDIM Valid_samp(0:35,1:Vsamp_size)
386   |   MAT Valid_samp= (0)
387   |   MAT Samp_count= (1)
388   |   Unfill_ct=0
389   |   Subset_len=5      ! SETS # OF POINTS PER SUBSET
390   |   Uspan=(Subset_len-1)/2
391   |   !
392   |   CALL Data_storm("5 1 2 >P/W","ACQ",0) ! ACQUIRES DIG. PTS TO FIND ABSOL
UTE MIN AND MAX
393   |   V_0_crude=MIN(Dig_array(*)) ! USED ONLY FOR UNFILL FUNCTION
394   |   V_1_crude=MAX(Dig_array(*))
395   |   Seg=(X_over2-X_over1)/36
396   |   !
397   |   REPEAT
398   |       PRINTER IS 1
399   |       CALL Data_storm("5 1 2 >P/W","ACQ",0) !ACQUIRES DIG PTS. FROM SCOPE AN
D STORES IN DIG_ARRAY(*)
400   |   |-----
401   |   Acquire:  ISELECTS SUBSETS OF X POINTS FROM DATA STREAM BETWEEN CROSSOVERS
402   |               !SUBSET ARE THE PTS. IN THE VALID INTERVAL RANGE PER WAVEFORM STORED
403   |       FOR Phs=0 TO 35
404   |           IF Samp_count(Phs)>Vsamp_size THEN GOTO Next_phs
405   |           Center=INT(X_over1+Phs*Seg)
406   |           FOR Point=(Center-Uspan) TO (Center+Uspan)
407   |               IF Samp_count(Phs)>Vsamp_size THEN GOTO Next_phs
408   |               !CHECKS DATA FOR ERRONEOUSLY FILLED POINTS AND DISREGARDS
409   |               Xfill=(Dig_array(Point-1)+Dig_array(Point+1))/2
410   |               IF ABS((Xfill-Dig_array(Point))/(V_1_crude-V_0_crude))>.002 THEN
411   |                   Valid_samp(Phs,Samp_count(Phs))=Dig_array(Point)! SAVES SELECTED PT
S IN SUBSET_PT(*)
412   |                   Samp_count(Phs)=Samp_count(Phs)+1
413   |               ELSE
414   |                   Remove:  !
415   |                       Unfill_ct=Unfill_ct+1 ! COUNTS # OF POINTS REMOVED
416   |                       PRINT TABXY(1,1),"POINT#";Point;"=" ";Dig_array(Point);" REMOVED DU
E TO LINEAR FILL
417   |                   END IF
418   |               NEXT Point
419   |               PRINT TABXY(10,Phs+4);Phs*10;"degree phase count=";Samp_count(Phs)
420   |       Next_phs:  NEXT Phs
421   |       Samp_compl=1
422   |       FOR Phs=0 TO 35
423   |           IF Samp_count(Phs)<Vsamp_size THEN Samp_compl=0
424   |       NEXT Phs
425   |       UNTIL Samp_compl=1 ! REPEAT UNTIL ALL 36 SUBSETS ARE FILLED
426   |       PRINT TABXY(1,1),"SAMPLE COMPLETE"
427   |       BEEP
428   |       BEEP
429   |   |*****
430   |   |*****   END OF SAMP_BUILDER SUBPROGRAM   *****

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```

431 |*****
432 SUBEND
433 |
434 |*****
435 SUB Occur_builder(Selector) | SELECTS V_1 & V_0
436 | CONVERTS VALID_SAMP(*) TO CELL# vs. OCCURRENCE
437 |*****
438 COM /Zip/ Subset_len,Subset_pt(*),Valid_pt(*),Samp_count(*),Unfill_ct,Bi
n_pt(*)
439 COM /Dig/ V_1,V_0,Vmiddle,Occur_ampl(*),Total_cells,0,Vsamp_size,Valid_s
amp(*),Cell_0,Cell_1,Ber,Phs
440 COM /Sig/ Best_fit_0(*),Best_fit_1(*),Sigma_0(*),Sigma_1(*),Unoccur_0,Un
occur_1,P_0(*),P_1(*),P_e(*),Q_0(*),Q_1(*)
441 COM /Vvv/ Vmin,Vmax,Vspan,Vcell
442 COM /Pp/ Printing,Comment$
443 Bounds: | THIS SECTION OBTAINS V_1,V_0 AND VMID(unnormalized)
444 | METHOD 1(SELECTOR=1)
445 | V_0 , V_1 WILL BE MANUALLY ENTERED BY OPERATOR
446 | METHOD 2(SELECTOR=2)
447 | V_0 , V_1 WILL BE CALCULATED BASED ON MAXIMAL OCCURRENCE
448 PRINTER IS Printing
449 PRINT CHR$(12);
450 PRINTER IS 1
451 IF Selector=1 THEN
452 PRINTER IS 1
453 PRINT "ENTER V_1 VALUE (in V)"
454 INPUT "V_1=?",V_1
455 PRINT "ENTER V_0 VALUE (in V)"
456 INPUT "V_0=?",V_0
457 Vmiddle=(V_1+V_0)/2
458 PRINTER IS Printing
459 PRINT "MANUALLY INPUT V_1,V_0 SEQUENCE"
460 PRINT "V_0=";V_0
461 PRINT "V_1=";V_1
462 PRINT "Vmiddle=";Vmiddle
463 Vmax=MAX(Valid_samp(*))
464 Vmin=MIN(Valid_samp(*))
465 Vspan=Vmax-Vmin
466 Vcell=Vspan/Total_cells
467 MAT Occur_ampl= (0)
468 FOR Jib=1 TO Vsamp_size
469 IF Valid_samp(Phs,Jib)<V_0 OR Valid_samp(Phs,Jib)>V_1 THEN Skot
470 IF Valid_samp(Phs,Jib)=V_1 THEN
471 Cell_no=Total_cells
472 GOTO Molk
473 END IF
474 Cell_no=INT((Valid_samp(Phs,Jib)-Vmin)/Vcell)+1
475 Molk: Occur_ampl(Cell_no)=Occur_ampl(Cell_no)+1
476 Skot: NEXT Jib
477 Cell_0=INT((V_0-Vmin)/Vcell)+1
478 Cell_1=INT((V_1-Vmin)/Vcell)+1
479 Unoccur_0=Occur_ampl(1)
480 Unoccur_1=Occur_ampl(Total_cells)
481 PRINTER IS Printing
482 PRINT " # OF OCCURRENCES IN ZERO(V_0) LEVEL CELL=";Unoccur_0
483 PRINT " # OF OCCURRENCES IN ONE(V_1) LEVEL CELL=";Unoccur_1
484 PRINTER IS 1
485 END IF
486 IF Selector=2 THEN
487 MAT Occur_ampl= (0)
488 |-----
489 | Vmin,Vmax,Vspan,Vcell IS FOR RECALCULATED FOR EACH PHASE SUBSET
490 |-----
491 Vmin=1.E+99
492 Vmax=-1.E+99
493 FOR Jib=1 TO Vsamp_size
494 IF Valid_samp(Phs,Jib)<Vmin THEN Vmin=Valid_samp(Phs,Jib)

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```

495     IF Valid_samp(Phs,Jib)>Vmax THEN Vmax=Valid_samp(Phs,Jib)
496     NEXT Jib
497     Vspan=Vmax-Vmin
498     Vcell=Vspan/Total_cells
499     |-----
500     | CELLS DATA POINTS
501     |-----
502     FOR Jib=1 TO Vsamp_size
503         IF Valid_samp(Phs,Jib)=Vmax THEN IRESETS MAX PT. INTO HIGHEST CELL
504         Cell_no=Total_cells
505         GOTO Qak
506         END IF
507         Cell_no=INT((Valid_samp(Phs,Jib)-Vmin)/Vcell)+1
508 Qak:   Occur_ampl(Cell_no)=Occur_ampl(Cell_no)+1
509 Skom:  NEXT Jib
510     |-----
511     | FINDS CELL# OF ZERO LEVEL (BASED ON MAXIMAL OCCURRENCE)
512     |-----
513     Bell=0
514     Cell_0=1
515     Block=INT(Total_cells/2)
516     FOR Jib=1 TO Block
517         IF Occur_ampl(Jib)>Bell THEN
518             Bell=Occur_ampl(Jib)
519             Cell_0=Jib      ! CELL # OF "0" LEVEL
520         END IF
521     NEXT Jib
522     |-----
523     | FINDS CELL# OF ONE LEVEL (BASED ON MAXIMAL OCCURRENCE)
524     |-----
525     Bell=0
526     Cell_1=0
527     FOR Jib=Block+1 TO Total_cells
528         IF Occur_ampl(Jib)>Bell THEN
529             Bell=Occur_ampl(Jib)
530             Cell_1=Jib      ! CELL # OF "1" LEVEL
531         END IF
532     NEXT Jib
533     V_0=(Cell_0-.5)*Vcell+Vmin ! VALUE OF "0" LEVEL IN mV
534     V_1=(Cell_1-.5)*Vcell+Vmin ! VALUE OF "1" LEVEL IN mV
535     Vmiddle=(V_0+V_1)/2
536     Unoccur_0=Occur_ampl(Cell_0) !UNNORMALIZED # OF OCCURRENCES IN CELL 0
537     Unoccur_1=Occur_ampl(Cell_1) !      "      "      "      "      "      1
538     PRINTER IS Printing
539     IF Selector=1 THEN PRINT "V_0,V_1 are manually entered"
540     IF Selector=2 THEN PRINT "V_0,V_1 calculated based on maximal occurren
ce"
541     PRINT
542     PRINT "Vmin=";Vmin;"   Vmax=";Vmax;"   Vspan=";Vspan;"   Vcell=";Vcell
543     PRINT "CELL # OF ZERO LEVEL =" ;Cell_0
544     PRINT " CELL # OF ONE LEVEL =" ;Cell_1
545     PRINT "V_0=";V_0
546     PRINT "V_1=";V_1
547     PRINT "Vmiddle=";Vmiddle
548     PRINT "# OF OCCURRENCES IN ZERO LEVEL(V_0) CELL=";Unoccur_0
549     PRINT " # OF OCCURRENCES IN ONE LEVEL(V_1) CELL=";Unoccur_1
550     PRINT
551     GOTO Noprint
552     PRINT "CELL#/ # OF OCCURRENCES IN CELL"
553     PRINT
554     FOR Jib=1 TO Total_cells
555         PRINT "CELL#";Jib;"=";Occur_ampl(Jib),
556     NEXT Jib
557 Noprint:  |
558     PRINTER IS 1
559     END IF
560 Flow:SUBEND

```

```

561 I
562 I
563 |*****
564 SUB Gc_sigma(Z) I
565 I SIGMA IS CALCULATED FOR THE GAUSSIAN CURVE
566 |*****
567 COM /Zip/ Subset_len,Subset_pt(*),Valid_pt(*),Samp_count(*),Unfill_ct,Bi
n_pt(*)
568 COM /Dig/ V_1,V_0,Vmiddle,Occur_ampl(*),Total_cells,D,Vsamp_size,Valid_s
amp(*),Cell_0,Cell_1,Ber,Phs
569 COM /Wave/ Wave$,Wavehead$,Dig_array(*),X_plot(*),Y_plot(*)
570 COM /Hpib/ Tek1,Tek2,Tek3,Tek4,Tek5,Tek6,Tek7,Tek8,Tek9,Hard_disk,Atten
driv,Scope,Freq_ct,Opt_pm,Opt_atten,Sweep_osc,Data_acq,Anr_ber,Anr_prog,Tek_ct
571 COM /Pp/ Printing,Comment$
572 COM /Sig/ Best_fit_0(*),Best_fit_1(*),Sigma_0(*),Sigma_1(*),Unoccur_0,Un
occur_1,P_0(*),P_1(*),P_e(*),Q_0(*),Q_1(*)
573 COM /Strait/ Vsamp_ave,Sig_0,Sig_1,V0_count,V1_count,V0_ave,V1_ave,V_zer
o,V_one,Q_zero(*),Q_one(*),P_zero(*),P_one(*),P_error(*)
574 COM /Vvv/ Vmin,Vmax,Vspan,Vcell
575 I
576 GOTO Skipper
577 |-----
578 I THIS SECTION FINDS ALL CELLS WITH NO OCCURRENCES
579 |-----
580 Mt_cells=0
581 PRINT "EMPTY CELL LOCATOR SECTION-- ALL CELLS LISTED ARE EMPTY"
582 PRINT
583 PRINT "CELL#'S";
584 FOR Jib=Cell_0 TO Cell_1
585 IF Occur_ampl(Jib)=0 THEN
586 PRINT Jib;
587 Mt_cells=Mt_cells+1
588 IF Mt_cells>50 THEN GOTO Too_many
589 END IF
590 NEXT Jib
591 Too_many: PRINT
592 PRINT "THE TOTAL # OF EMPTY CELL= ";Mt_cells
593 IF Mt_cells=0 THEN
594 Min_occur=9.E+150
595 FOR Sx=1 TO Total_cells
596 IF Occur_ampl(Sx)<Min_occur THEN
597 Min_occur=Occur_ampl(Sx)
598 D_cell=Sx
599 END IF
600 NEXT Sx
601 I D=Vmin+(D_cell-.5)*Vcell I UN-NORMALIZED D
602 ELSE
603 I D=Vmin+(.5)*Vspan I UN-NORMALIZED D
604 END IF
605 I
606 |-----
607 I THIS SECTION CALCULATES SIGMA 0 & 1 USING STRAIGHT STATS
608 |-----
609 Skipper: I
610 Vsamp_ave=0
611 FOR Jib=1 TO Vsamp_size
612 Vsamp_ave=Vsamp_ave+Valid_samp(Phs,Jib)
613 NEXT Jib
614 Vsamp_ave=DROUND(Vsamp_ave/Vsamp_size,6)
615 V0_count=0
616 V1_count=0
617 V0_ave_s=0
618 V1_ave_s=0
619 FOR J=1 TO Vsamp_size
620 IF Valid_samp(Phs,J)<=Vsamp_ave THEN
621 V0_count=V0_count+1
622 V0_ave_s=V0_ave_s+Valid_samp(Phs,J)

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```

623     ELSE
624         V1_count=V1_count+1
625         V1_ave_s=V1_ave_s+Valid_samp(Phs,J)
626     END IF
627 NEXT J
628 |
629 V0_ave=DROUND(V0_ave_s/V0_count,6)
630 V1_ave=DROUND(V1_ave_s/V1_count,6)
631 |
632 Sig_1_sum=0
633 Sig_0_sum=0
634 FOR J=1 TO Vsamp_size
635     IF Valid_samp(Phs,J)<=Vsamp_ave THEN
636         Sig_0_sum=Sig_0_sum+(Valid_samp(Phs,J)-V0_ave)^2
637     ELSE
638         Sig_1_sum=Sig_1_sum+(Valid_samp(Phs,J)-V1_ave)^2
639     END IF
640 NEXT J
641 Sig_0=DROUND(SQR(Sig_0_sum/(V0_count-1)),6)
642 Sig_1=DROUND(SQR(Sig_1_sum/(V1_count-1)),6)
643 IF Z=0 THEN Sigma_out
644     PRINTER IS Printing
645     PRINT "STATISTICAL CALCULATIONS SECTION @ ";Phs*10;" DEGREES PHASE"
646     PRINT "Vphase subset ave=";Vsamp_ave
647     PRINT
648     PRINT "V(0) AVE=";V0_ave,
649     PRINT "V(1) AVE=";V1_ave
650     PRINT "V(0) COUNT=";V0_count,
651     PRINT "V(1) COUNT=";V1_count
652     PRINT "SIGMA 0=";Sig_0,
653     PRINT "SIGMA 1=";Sig_1
654     PRINTER IS 1
655     |
656 Sigma_out: SUBEND
657 |
658 |
659 |*****
660 SUB Prob_error(Z) !CALCULATES BER given sigma_0,sigma1,V_0,V_1,D
661 |*****
662 COM /Dig/ V_1,V_0,Vmiddle,Occur_ amp(*),Total_cells,D,Vsamp_size,Valid_s
amp(*),Cell_0,Cell_1,Ber,Phs
663 COM /Sig/ Best_fit_0(*),Best_fit_1(*),Sigma_0(*),Sigma_1(*),Unoccur_0,Un
occur_1,P_0(*),P_1(*),P_e(*),Q_0(*),Q_1(*)
664 COM /Strait/ Vsamp_ave,Sig_0,Sig_1,V0_count,V1_count,V0_ave,V1_ave,V_ze
ro,V_one,Q_zero(*),Q_one(*),P_zero(*),P_one(*),P_error(*)
665 COM /Vvv/ Vmin,Vmax,Vspan,Vcell
666 COM /Pp/ Printing,Comment$
667 Q_zero(Phs)=DROUND((ABS(D-V_zero))/Sig_0,6) ! CALC. Q0
668 P_zero(Phs)=DROUND(1/(Q_zero(Phs)*SQR(2*PI))*(1-1/((Q_zero(Phs))^2))*E
XP(-((Q_zero(Phs))^2)/2),6)! CALC. P_0
669 ! WHERE P_ZERO IS THE PROB. OF A "0" BEING MISTAKEN FOR A "1"
670 Q_one(Phs)=DROUND((ABS(D-V_one))/Sig_1,6) ! CALC. Q1
671 P_one(Phs)=DROUND(1/(Q_one(Phs)*SQR(2*PI))*(1-1/((Q_one(Phs))^2))*EXP(
-((Q_one(Phs))^2)/2),6)! CALC. P_1
672 ! WHERE P_1 IS THE PROB. OF A "1" BEING MISTAKEN FOR A "0"
673 P_error(Phs)=DROUND((P_zero(Phs)*V0_count+P_one(Phs)*V1_count)/Vsamp_s
ize,5)
674 |
675 IF Z=0 THEN Prob_out
676 PRINTER IS Printing
677 PRINT "*****PROBABILITY OF ERROR CALCULATIONS (using Dopt from 180 degre
e SUBSET)*****"
678 | PRINT "*****
*****"
679 |
680 PRINT "Q_0=";Q_zero(Phs);
681 PRINT " PROB. OF 0 BEING MISTAKEN FOR A 1= P_0 =";P_zero(Phs)

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```

682     PRINT "Q_1=";Q_one(Phs);
683     PRINT "   PROB. OF 1 BEING MISTAKEN FOR A 0= P_1 =" ;P_one(Phs)
684     PRINT "TOTAL PROB. OF ERROR= P_E =" ;P_error(Phs)
685     PRINTER IS 1
686     !
687 Prob_out:  SUBEND
688 |*****
689 SUB Kbd_interrupt
690 |*****
691 |-----|
692 |               *****KEYBOARD INTERRUPT***** |
693 |-----|
694 |
695 Kbd_interrupt:          ! KBD INTERRUPT
696     BEEP 4000,.2
697     BEEP 3600,.2
698     PRINTER IS 1
699     DISP "INVALID KEY HAS BEEN SELECTED!!!"
700     WAIT .4
701 SUBEND
702 |*****
703 SUB Wef_plot(Xmax,Ymax,Xax$,Yax$,Title$,Plot_xy(*)) !PLOTS OCCUR vs CELL
704 |*****
705 COM /Pp/ Printing,Comment$
706 SYSTEM PRIORITY 0
707 OFF KEY
708 PRINTER IS 1
709 PRINT CHR$(12)
710 GRAPHICS ON
711 GINIT
712 VIEWPORT 0,130,0,100
713 FRAME
714 LORG 5
715 CSIZE 5
716 MOVE 70,95
717 LABEL Title$
718 CSIZE 5
719 MOVE 65,4
720 LABEL Xax$
721 MOVE 5,50
722 DEG
723 LDIR 90
724 LABEL Yax$
725 LDIR 0
726 VIEWPORT 20,120,14,90
727 FRAME
728 WINDOW 0,Xmax,0,Ymax
729 CLIP OFF
730 CSIZE 4
731 LORG 8
732 FOR I=0 TO 10
733 MOVE -Xmax*.01,Ymax*.1*I
734 LABEL USING "DDDD";Ymax*.1*I ! LABELS Y-AXIS
735 NEXT I
736 LORG 6
737 FOR I=0 TO 10
738 MOVE Xmax*.1*I,-Ymax*.01
739 LABEL USING "DDD";Xmax*.1*I
740 NEXT I
741 CLIP ON
742 FOR I=0 TO 10
743 LINE TYPE 4
744 MOVE 0,Ymax*I*.1
745 DRAW Xmax,Ymax*I*.1
746 LINE TYPE 3
747 MOVE Xmax*I*.1,0
748 DRAW Xmax*I*.1,Ymax

```

```

749 NEXT I
750 LINE TYPE 1
751 FOR I=0 TO 50
752 MOVE 0,Ymax*I*.02
753 DRAW Xmax*.01,Ymax*I*.02 ! DRAW Y-AXIS TICKS
754 MOVE Xmax*I*.02,0
755 DRAW Xmax*I*.02,Ymax*.015 ! DRAW X-AXIS TICKS
756 NEXT I
757 MOVE 1,Plot_xy(1)
758 FOR I=1 TO Xmax
759 PLOT I,Plot_xy(I) ! PLOTS OCCURRENCE PARAMETER
760 NEXT I
761 Esc$=""
762 PRINT Printing;Esc$&"&a15C" ! MOVES CURSOR TO COLUMN 15
763 PRINT Printing;Esc$&"*r1A" ! STARTS GRAPHICS AT CURRENT CURSOR
764 DUMP GRAPHICS
765 !
766 SUBEND
767 !
768 !*****
769 SUB Data_storm(P_w$,Ave_acq$,Xfer_only)
770 !*****
771 ! VERSION 2D-(11/13/86)-WEF
772 ! VERSION 3D-(12/04/86)-WEF- DATA STORM MOD. FOR IMPROVED SPEED
773 !XFER_ONLY=1 FOR ARRAY XFER ONLY,NO AQR
774 !AVE_ACQ="ACQ" FOR PSEUDO,"AVE" FOR AVE
775 !EX. P_W$="5 12 >P/W" FOR 512 PTS/WVM
776 ! VERSION 4D-(4/05/87)-WEF- DATA STORM MOD. FOR IMPROVED SPEED
777 !LABELS CHANGED TO PRINT TABXY
778 !SCOPE UNHANG SOFTWARE ADDED
779 ! PROGRAM ACQUIRES WAVEFORM FROM SCOPE,FINDS MULTIPLIERS AND DATA
780 ! MATRIX
781 !*****
782 COM /Wave/ Wave$,Wavehead$,Dig_array(*),X_plot(*),Y_plot(*)
783 COM /Hpib/ Tek1,Tek2,Tek3,Tek4,Tek5,Tek6,Tek7,Tek8,Tek9,Hard_disk,Atten_dr
iv,Scope,Freq_ct,Opt_pm,Opt_atten,Sweep_osc,Data_acq,Anr_ber,Anr_prog,Tek_ct
784 COM /Pp/ Printing,Comment$
785 COM /Dstorm/ P_w,Xzero,Xmult,Xun$,Yzero,Ymult,Yun$
786 !*****
787 !NORMALIZED HORIZ.&VERT. TIME BASE MUST BE PRESET BEFORE CALLING DATA_STORM
788 SYSTEM PRIORITY 0
789 OFF KEY
790 DISP ""
791 ! NOTE: SAMPLING UNIT MUST BE SET BEFORE CALL DATASTORM . OTHERWISE THE C
URRENT UNIT WILL BE USED!!
792 GOTO Faster
793 GCLEAR
794 GRAPHICS ON
795 CSIZE 15
796 MOVE 20,80
797 LABEL "DATA STORM"
798 MOVE 15,60
799 LABEL "IN PROGRESS"
800 CSIZE 10
801 MOVE 15,35
802 LABEL "DO NOT DISTURB!!!"
803 Faster: PRINTER IS 1
804 PRINT TABXY(25,17),"DATA STORM IN PROGRESS"
805 PRINT TABXY(25,18)," DO NOT DISTURB!"
806 IF Xfer_only=1 THEN GOTO Yank
807 !-----
808 ON TIMEOUT 7,4 GOSUB Un_hang
809 OUTPUT Scope;P_w$ ! SETS THE # OF POINTS/WAVEFORM
810 OUTPUT Scope;"SCOPE" ! SCOPE
811 IF Ave_acq$="ACQ" THEN GOTO Eye_acq ! IF= "ACQ" ACQUIRES WAVEFORM
812 OUTPUT Scope;" 1 0 AVG" ! ELSE,INITIATES TEK7854 AVE. SAMPLING
813 GOTO Yank

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814 Eye_acq: OUTPUT Scope;"SCOPE AOR"           I INITIATES SCOPE ACQUIRE
815 Yank: OUTPUT Scope;"STORED DOT"           I CLEARS AOR ERROR
816     Spx=0
817     OUTPUT Scope;"0 WFM SENDX" I PUTS WFM # INTO X REG., SENDS
                                         WAVEFORM TO TEK OUTPUT BUFFER

818     IIF Spx<>210 THEN 1206
819     WAIT .5
820     ENTER Scope;P_w,Xzero,Xmult,Yzero,Ymult
821     REDIM Dig_array(1:P_w)
822     ENTER Scope;Dig_array(*)
823     OUTPUT Scope;"SCOPE"
824     OFF DELAY
825     GOTO No_preamble
826     I
827 Un_hang:   I UNHANGS TEK SCOPE
828           CLEAR 708
829           OFF TIMEOUT
830           FOR I=1 TO 10
831             BEEP I*1000,.1
832           NEXT I
833           GOTO Faster
834     RETURN
835     ENTER Scope;Wavehead$,Wave$           I STORES HEADING AND DATA STREAM
                                         IN STRING VARIABLES

836 |*****
837 | THIS SECTION ACQUIRES P/W,SCALE FACTORS AND OFFSETS FROM WAVEHEADS
838 |*****
839     Colon=POS(Wavehead$,CHR$(58))+1
840     Wavehead$=Wavehead$[Colon]           I REMOVES WFMPRE ENCDG:
841     Colon=POS(Wavehead$,CHR$(58))+1
842     Wavehead$=Wavehead$[Colon]           I REMOVES ASC,NR.PT:
843     Comma=POS(Wavehead$,CHR$(44))-1
844     P_w=VAL(Wavehead$[1,Comma])           I ACQUIRES P/W FROM WAVEHEAD
845     Colon=POS(Wavehead$,CHR$(58))+1           I FINDS POS. OF CHAR. AFTER COLON
846     Wavehead$=Wavehead$[Colon]
847     Colon=POS(Wavehead$,CHR$(58))+1
848     Wavehead$=Wavehead$[Colon]           I REMOVES ALL THRU XZERO:
849     Comma=POS(Wavehead$,CHR$(44))-1
850     Xzero=VAL(Wavehead$[1,Comma])           I ACQUIRES XZERO FROM WAVEHEAD
851     Colon=POS(Wavehead$,CHR$(58))+1
852     Wavehead$=Wavehead$[Colon]           I REMOVES ALL THRU XINCR:
853     Comma=POS(Wavehead$,CHR$(44))-1
854     Xmult=VAL(Wavehead$[1,Comma])           I ACQUIRES XMULT FROM WAVEHEAD
855     Colon=POS(Wavehead$,CHR$(58))+1
856     Wavehead$=Wavehead$[Colon]           I REMOVES ALL THRU XUNIT:
857     Comma=POS(Wavehead$,CHR$(44))-1
858     Xun$=Wavehead$[1,Comma]           I ACQUIRES XUNITS STRING VAR.
859     Colon=POS(Wavehead$,CHR$(58))+1
860     Wavehead$=Wavehead$[Colon]           I REMOVES ALL THRU YZERO:
861     Comma=POS(Wavehead$,CHR$(44))-1
862     Yzero=VAL(Wavehead$[1,Comma])           I ACQUIRES YZERO FROM WAVEHEAD
863     Colon=POS(Wavehead$,CHR$(58))+1
864     Wavehead$=Wavehead$[Colon]           I REMOVES ALL THRU YMULT:
865     Comma=POS(Wavehead$,CHR$(44))-1
866     Ymult=VAL(Wavehead$[1,Comma])           I ACQUIRES YMULT FROM WAVEHEAD
867     Colon=POS(Wavehead$,CHR$(58))+1
868     Wavehead$=Wavehead$[Colon]           I REMOVES ALL THRU YUNIT:
869     Semi_col=POS(Wavehead$,CHR$(59))-1
870     Yun$=Wavehead$[1,Semi_col]           I ACQUIRES YUNITS STRING VAR.
871 |*****
872 |*****
873 | THIS SECTION REMOVES COMMAS FROM DATA STREAM AND PLACES DATA POINTS
      INTO NORMALIZED(-4 TO 4) NUMERIC ARRAY DIG_ARRAY(*) PT#1 THRU P_W
874 |*****
875     Wave$=Wave$[6]
876     FOR I=1 TO P_w-1
877       Comma=POS(Wave$,CHR$(44))-1

```

```

878     Dig_array(I)=VAL(Wave$(1,Comma))
879     Wave$=Wave$(Comma+2)
880     NEXT I
881     Dig_array(I)=VAL(Wave$)
882     PRINTER IS 1
883     PRINT "TRANSMISSION AND ARRAY STORE COMPLETE"
884     OUTPUT Scope;"SCOPE"           I SELECT SCOPE MODE
885     GOTO No_preamble
886 |*****
887     PRINTER IS Printing
888     PRINT
889     PRINT
890     PRINT "          POINTS PER WAVEFORM= ";P_w
891     PRINT "                Xoffset= ";Xzero
892     PRINT "                Xmultiplier ";Xmult
893     PRINT "                Xunits= ";Xun$
894     PRINT "                Yoffset= ";Yzero
895     PRINT "                Ymultiplier= ";Ymult
896     PRINT "                Yunits= ";Yun$
897     PRINT
898     PRINT
899     PRINT " ABSOLUTE DATA w/ MULT. AND OFFSETS"
900 No_preamble:PRINTER IS 1
901         PRINT TABXY(25,17),"          "
902         PRINT TABXY(25,18),"          "
903 |*****
904 |***** END OF SUBPROGRAM DATA STORM *****
905 |*****
906 SUBEND
907 |-----
908 |
909 |*****

```

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Vita

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BIT ERROR RATE CHARACTERIZATION OF HIGH FREQUENCY DIGITAL SIGNALS UTILIZING SAMPLING TECHNIQUES

by

William E. Fulmer

Abstract

This thesis develops a bit error rate (BER) measurement technique based on the gaussian statistics of noise in high frequency baseband digital signals. Commercial BER test equipment is currently available, but is very expensive and requires the use of a known transmitted test pattern.

The laboratory implementation of this technique utilized a Tektronix digitizing oscilloscope to sample the signal and a HP minicomputer to process the data. Experiments were designed to cover a wide range of BER values and plots were made of BER vs. clock phase. It was found that when the noise was "purely" gaussian, there was excellent agreement between measured and predicted BERs at 1 Gb/s bit rates. A matching filter was required in order to achieve these results.

The predicted BER of an optical regenerator was characterized at 1.7 Gb/s at the decision circuit input and showed fair agreement with that measured. Discrepancies as great as an order of magnitude were observed at the BER minimum. This was attributed partially to the error detector limitations and also to the non-gaussian phenomena in the regenerator.

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